

Spatial ALD research at LMGP

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Laboratoire des Matériaux et du Génie Physique (Grenoble-INP/CNRS)

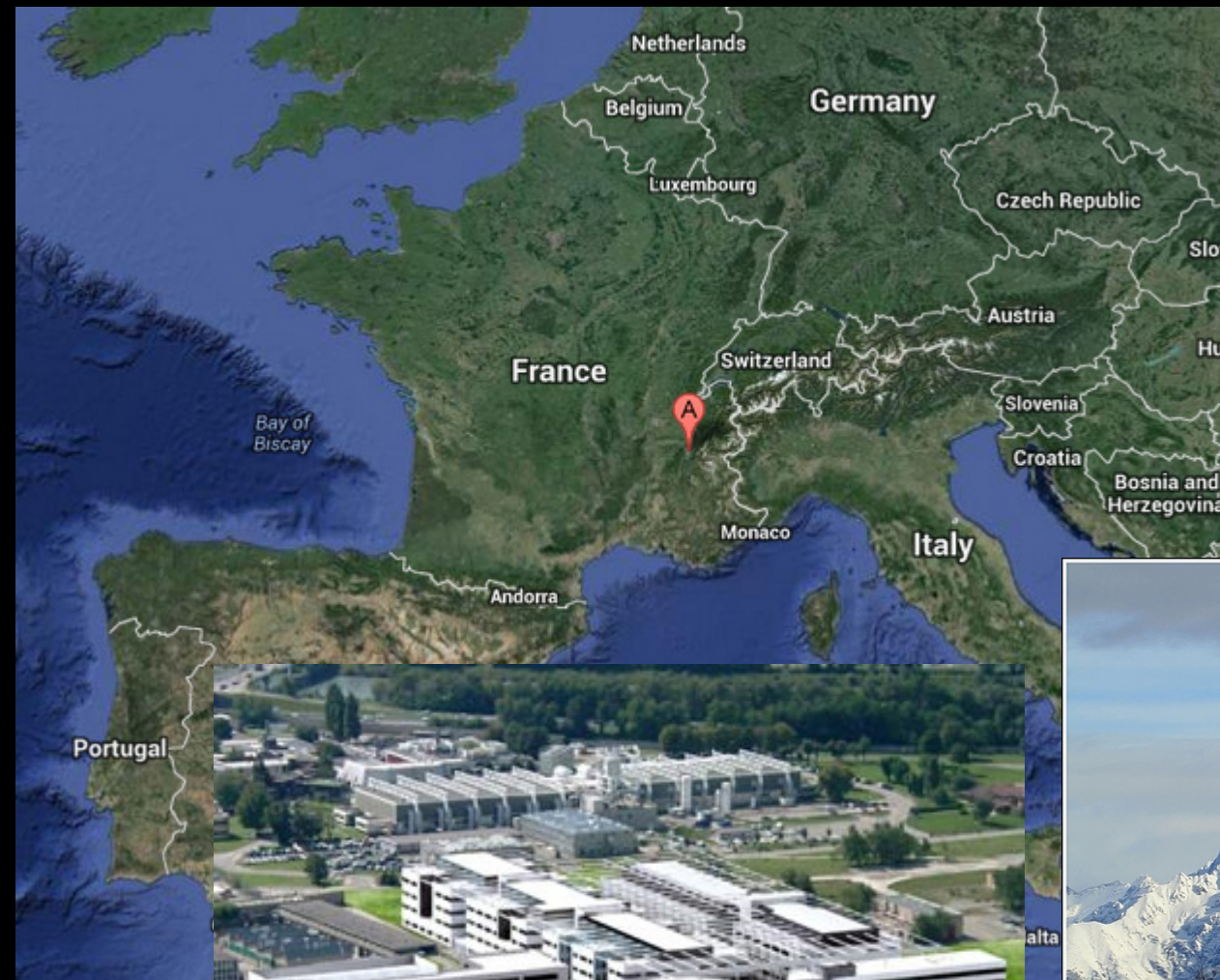
Spatial ALD day, TU/e, Eindhoven, The Netherlands

9th June 2022



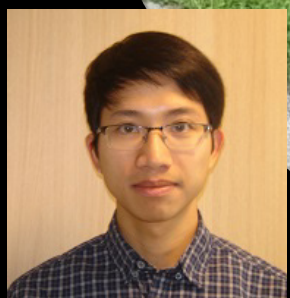


Where are we?





Thanks to the SALD Team!



Acknowledgements

• FUNDING



• COLLABORATORS



Patented 1977, Suntola et al.



United States Patent [19] **4,058,420** [11]
Suntola et al. [45] **Nov. 5, 1977**

[54] **METHOD FOR PRODUCING COMPOUND THIN FILMS**

[76] Inventors: **Tuomo Suntola**, Riihikallio, 02610 Espoo 61, Finland; **Jorma Antson**, Urheilutie 22, 01350, Vantaa 35, Finland

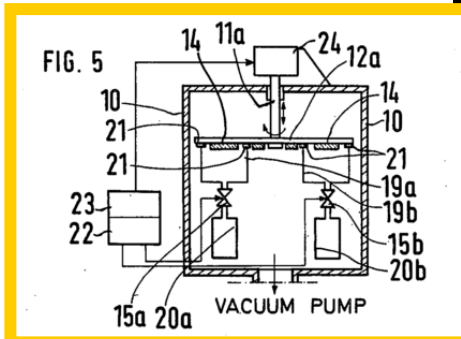
[21] Appl. No.: 635,233

[22] Filed: Nov. 25, 1975

[30] Foreign Application Priority Data
 Nov. 29, 1974 Finland 743473

[51] Int. Cl.² B05D 5/00; B05D 5/12
 [52] U.S. Cl. 156/611; 118/49

element at a temperature sufficiently high for the reac-



United States Patent [19] **4,389,973** [11]
Suntola et al. [45] **Jun. 28, 1983**

[54] **APPARATUS FOR PERFORMING GROWTH OF COMPOUND THIN FILMS** [56] **References Cited**

[75] Inventors: **Tuomo S. Suntola**; **Arto J. Pakkala**; **Sven G. Lindfors**, all of Espoo, Finland

[73] Assignee: **On-Labio AB**, Viikola, Finland

[21]

| U.S. PATENT DOCUMENTS | | | |
|-----------------------|--------|-------------------|-------------|
| 3,602,192 | 8/1971 | Grockowski | 118/719 |
| 3,721,583 | 3/1973 | Blakeslee | 156/611 |
| 3,825,439 | 7/1974 | Tick | 427/93 X |
| 3,964,937 | 6/1976 | Post et al. | 427/255.7 X |
| 4,015,558 | 4/1977 | Small et al. | 118/719 X |
| | | | 118/719 |

SALD at Atm. Pressure, no vacuum

APPLIED PHYSICS LETTERS 92, 19210 (2008)

Stable ZnO thin film transistors by fast open air atomic layer deposition

David H. Levy,^{a)} Diane Freeman, Shelby F. Nelson, Peter J. Cowdery-Corvan, and Lyn M. Irving
Research Laboratories, Eastman Kodak Company, Rochester, New York 14650-2102, USA



(Received 2 April 2008; accepted 17 April 2008; published online 12 May 2008)

We report stable, high performance zinc oxide thin film transistors grown by an atmospheric pressure atomic layer deposition system. With all deposition and processing steps kept at or below 200 °C, the alumina gate dielectric shows low leakage (below 10⁻⁸ A/cm²) and high breakdown fields. Zinc oxide thin film transistors in a bottom gate geometry yield on/off ratios above 10⁸, near zero turn-on voltage, little or no hysteresis, and mobility greater than 10 cm²/V s. With alumina passivation, shifts in threshold voltage under gate bias stress compare favorably to those reported in the literature. © 2008 American Institute of Physics. [DOI: 10.1063/1.2924768]

APPLIED PHYSICS LETTERS 93, 172111 (2008)

Reproducible growth of p-type ZnO:N using a modified atomic layer deposition process combined with dark annealing

L. Dunlop,^{a)} A. Kursumovic, and J. L. MacManus-Driscoll
Department of Materials Science, University of Cambridge, Pembroke St., Cambridge CB2 3RQ, United Kingdom

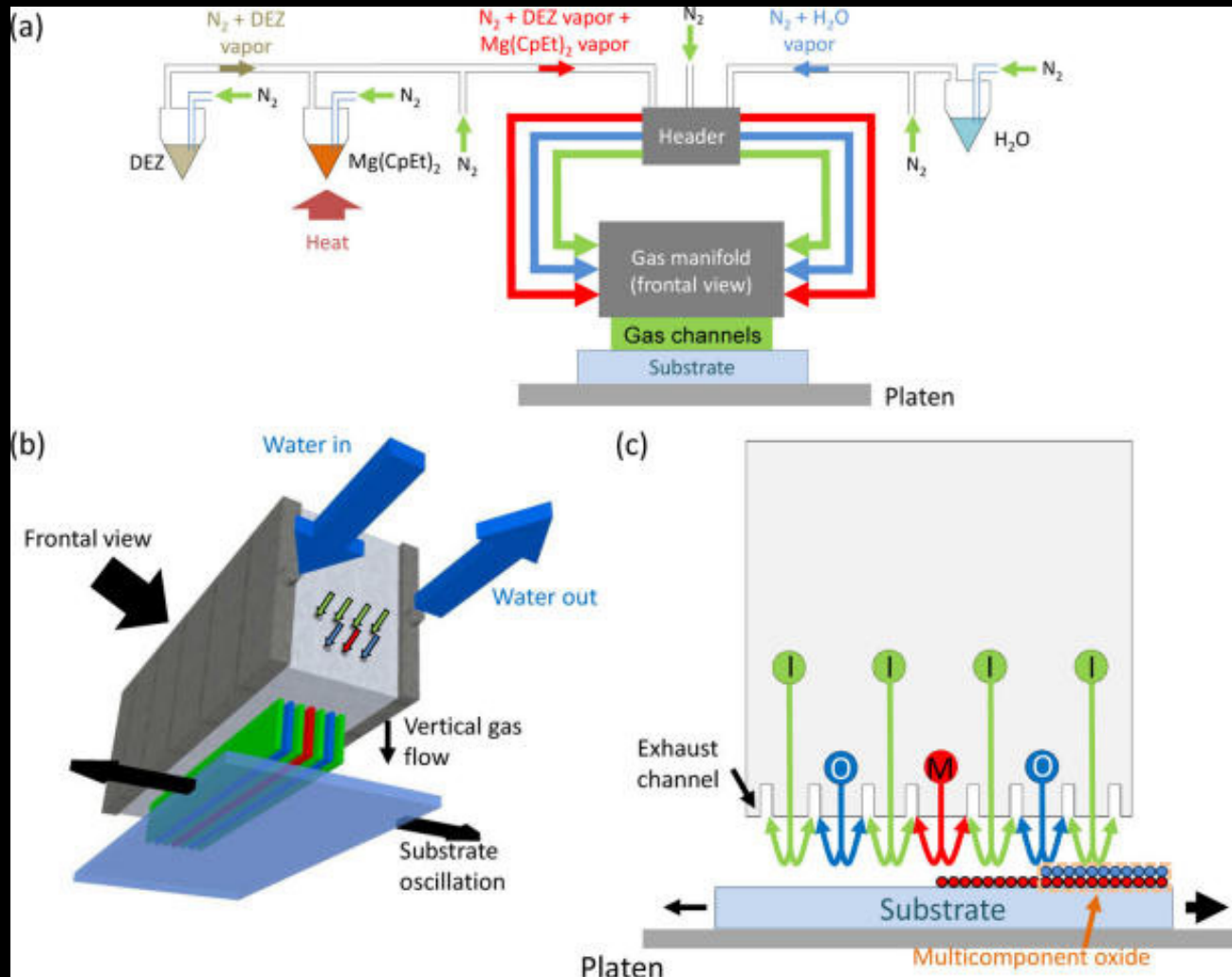


(Received 8 July 2008; accepted 16 September 2008; published online 31 October 2008)

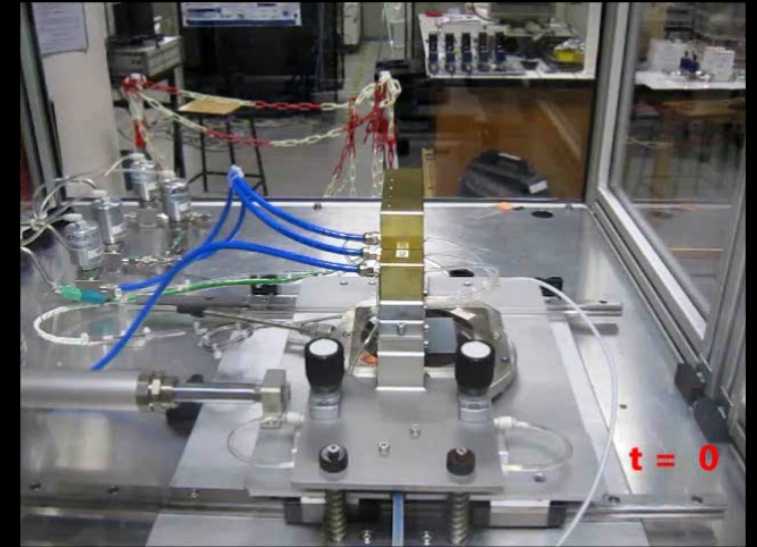
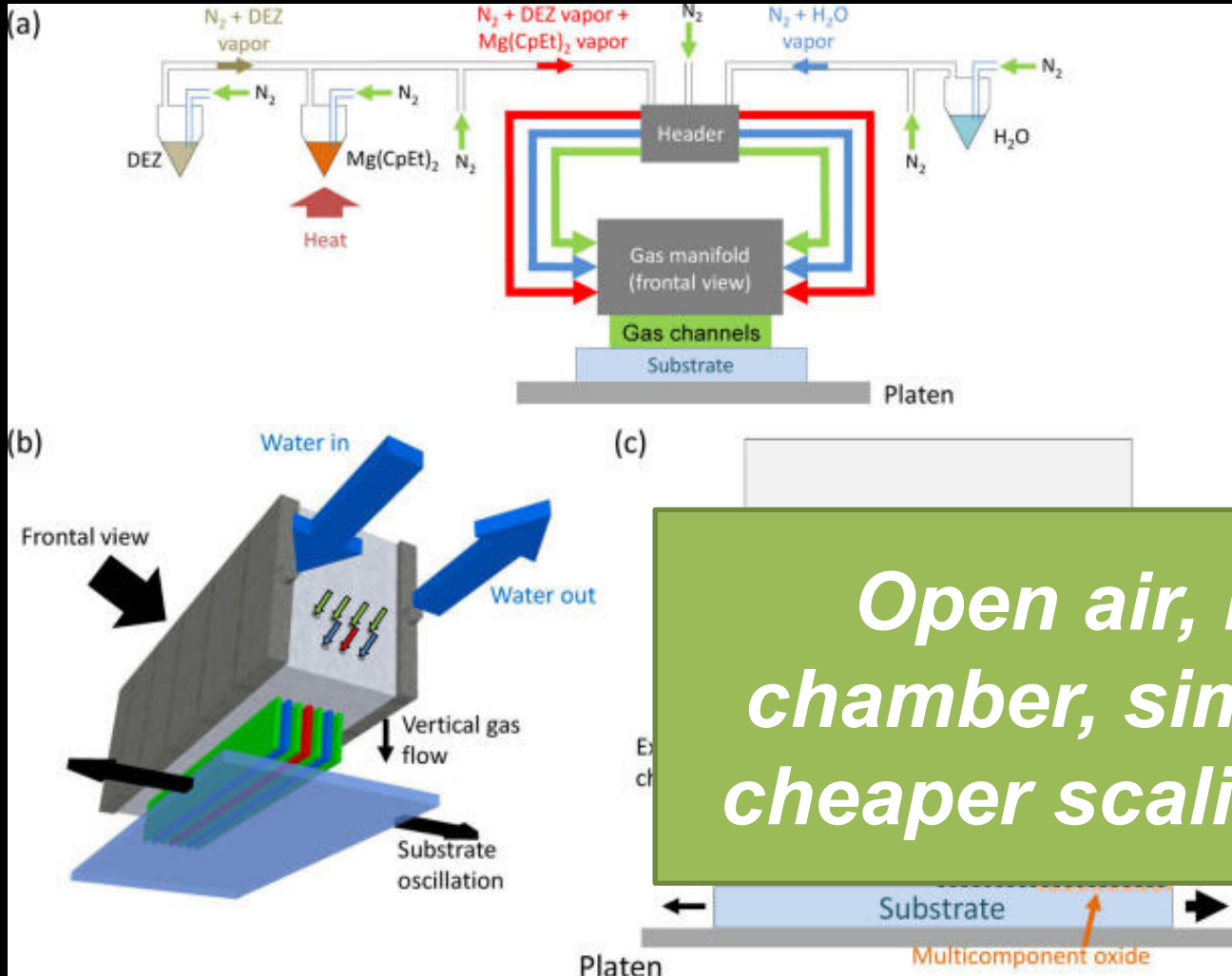
Nitrogen doped ZnO (ZnO:N) films were deposited by atmospheric atomic layer deposition (ALD) between 100 and 300 °C. Postannealing was required to remove compensating defects. Low temperature dark annealing, originally *n*-type films became *p*-type. Films deposited at low temperatures (≤150 °C) have low hole mobilities (μ) of 0.2–0.4 cm² V⁻¹ s⁻¹ and moderate carrier concentrations (n_p) of around 1 × 10¹⁵ cm⁻³. Higher temperature deposited films (≥200 °C) have higher μ values (6 cm² V⁻¹ s⁻¹) but n_p values < 1 × 10¹³ cm⁻³. This crossover in carrier properties can be explained by the opposing effects of deposition temperature on nitric oxide level and distribution, and film crystallinity. © 2008 American Institute of Physics. [DOI: 10.1063/1.3000604]



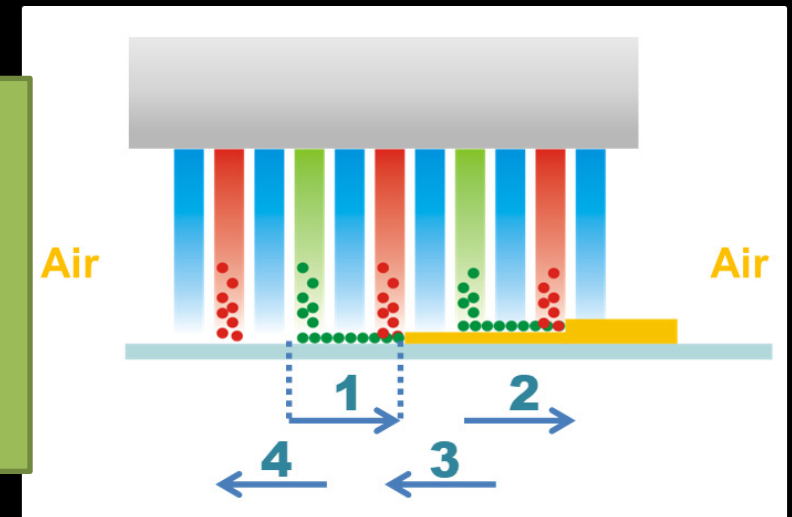
Based on a close-proximity, manifold injection head



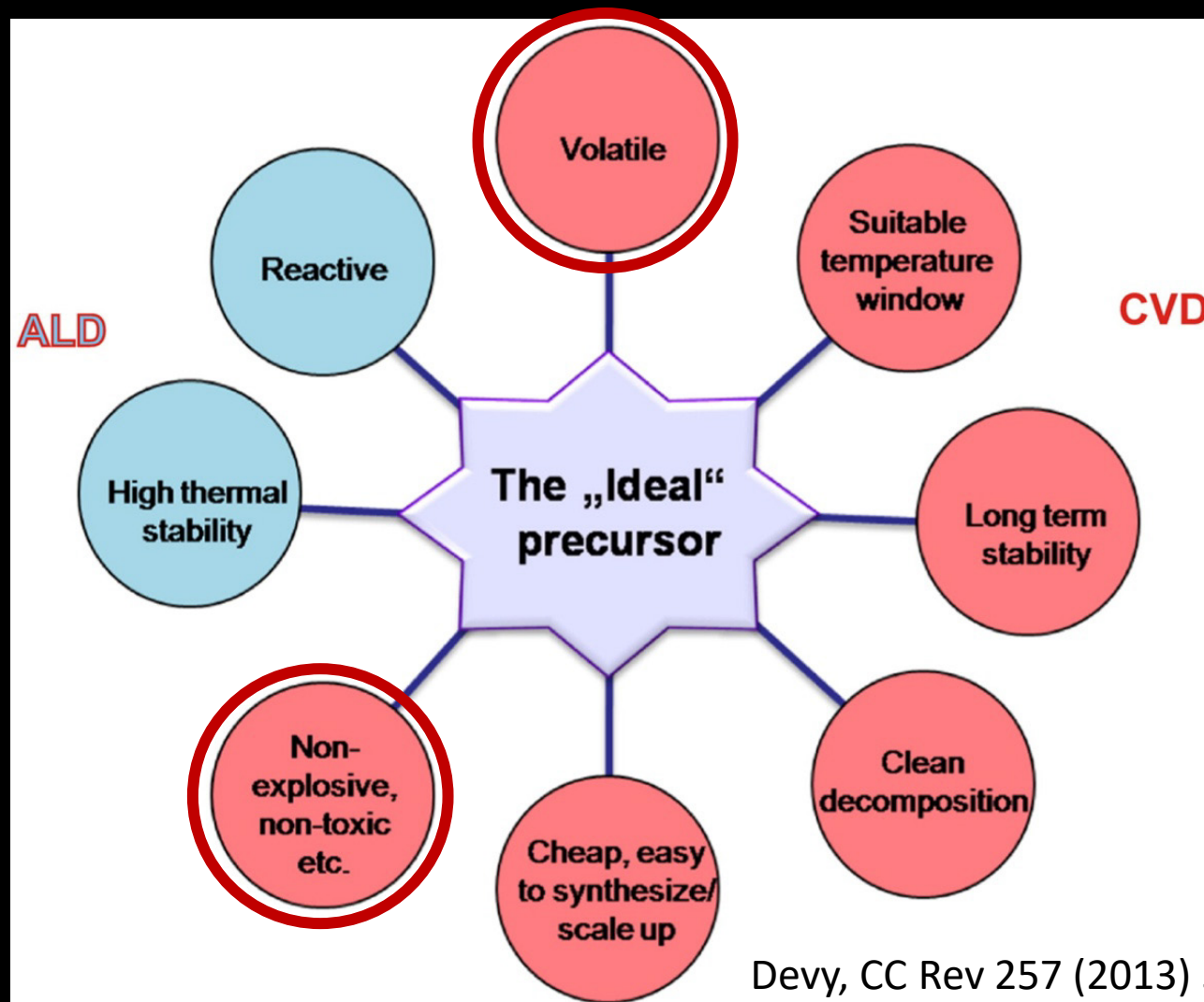
Based on a close-proximity, manifold injection head



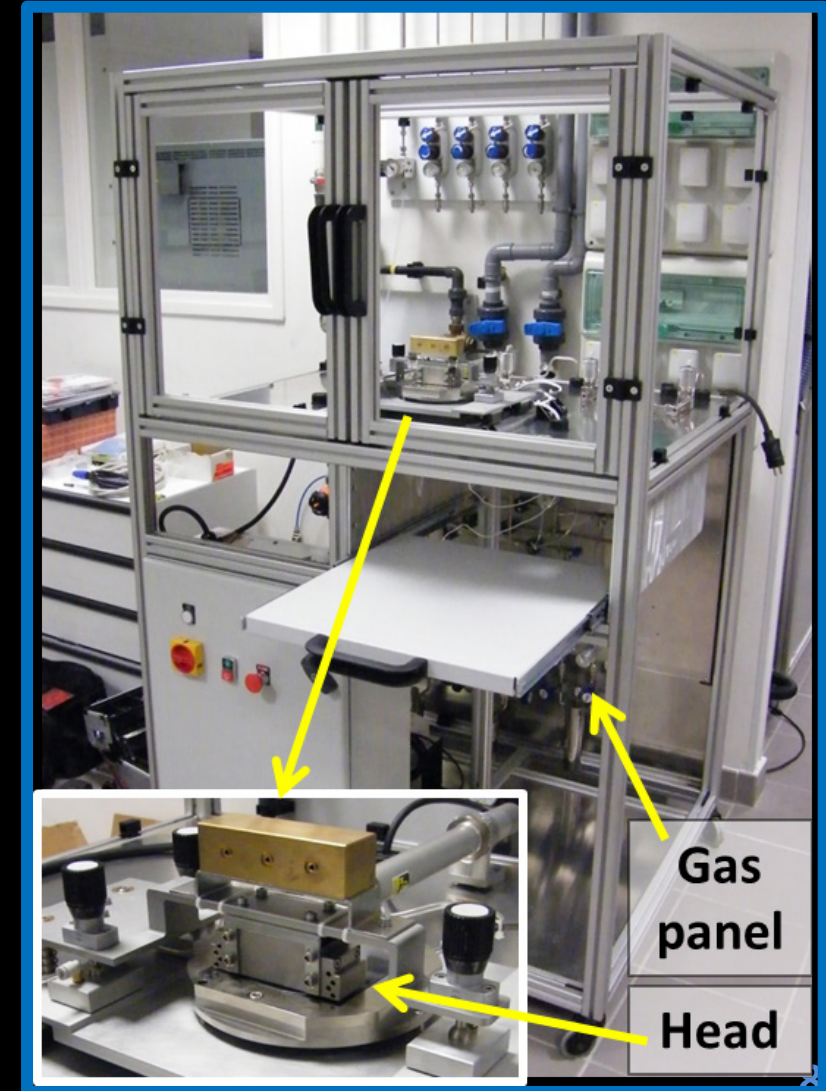
Open air, no chamber, simpler, cheaper scaling up



Open air, no chamber, simpler, cheaper scaling up



Devy, CC Rev 257 (2013) 3332



SPECIFICATION OF THE SALD

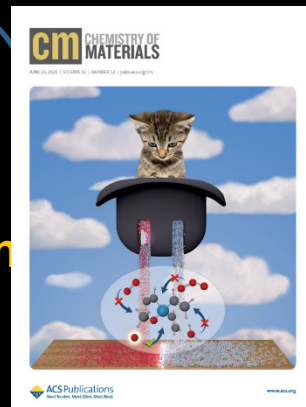
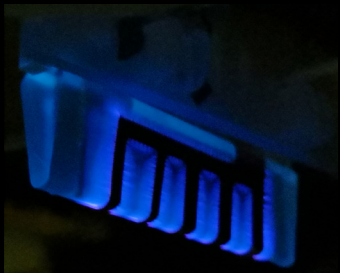
| | |
|------------------------------|--------------------------------|
| Deposition Temperature | RT to 350 °C |
| Deposition Area | 1 to 25 cm ² |
| Growth rate | Up to 2 nm/s |
| Substrates | Metal, glass, plastic, tissue, |
| Maximum Achievable Thickness | Up to several μm |

Materials available or in study:

ZnO, Al₂O₃, Al:ZnO, Cu, Cu₂O, CuO, TiO₂, SiO_x, MgO, SnO₂, Ga₂O₃, HfO₂, Ag, CeO₂, ZrO₂, Pd, Hybrids (Metalcones, MOFs, ...)

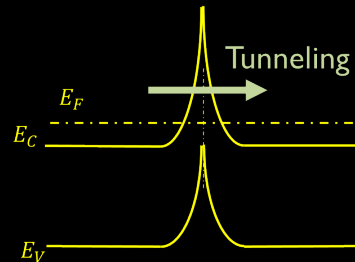
Design & Optimization

- Atm. Plasma activation
- up-scaling/simulation



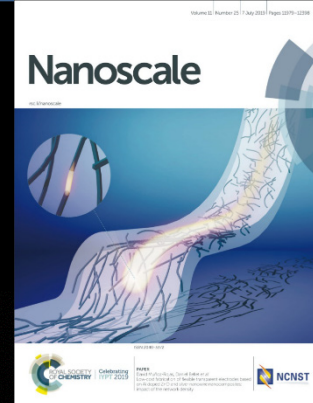
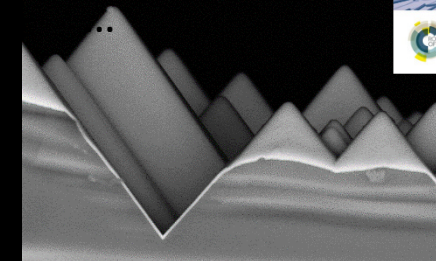
Fundamental studies

- Effect of open-air processing
- New materials

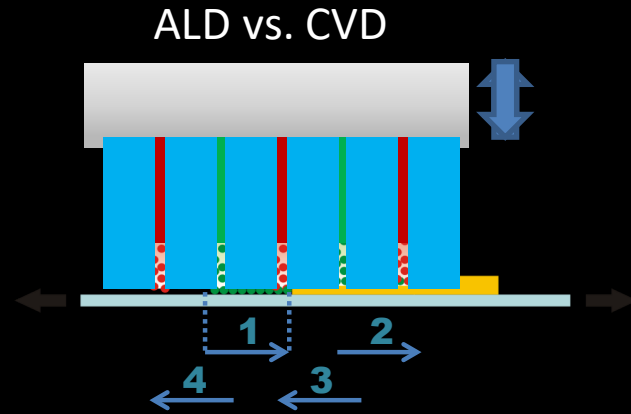


Applications

- TCM
- PV
- Sensors
- Res.Swicc.

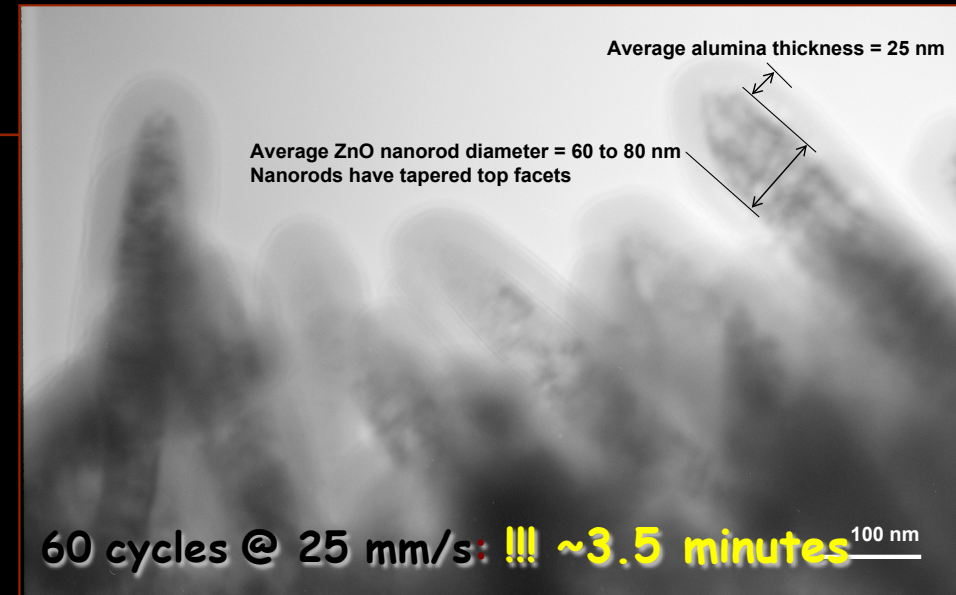


Possibility to perform CVD



40 cycles @ 2 mm/s: ~25 minutes

20 cycles @ 2 mm/s: ~12 minutes

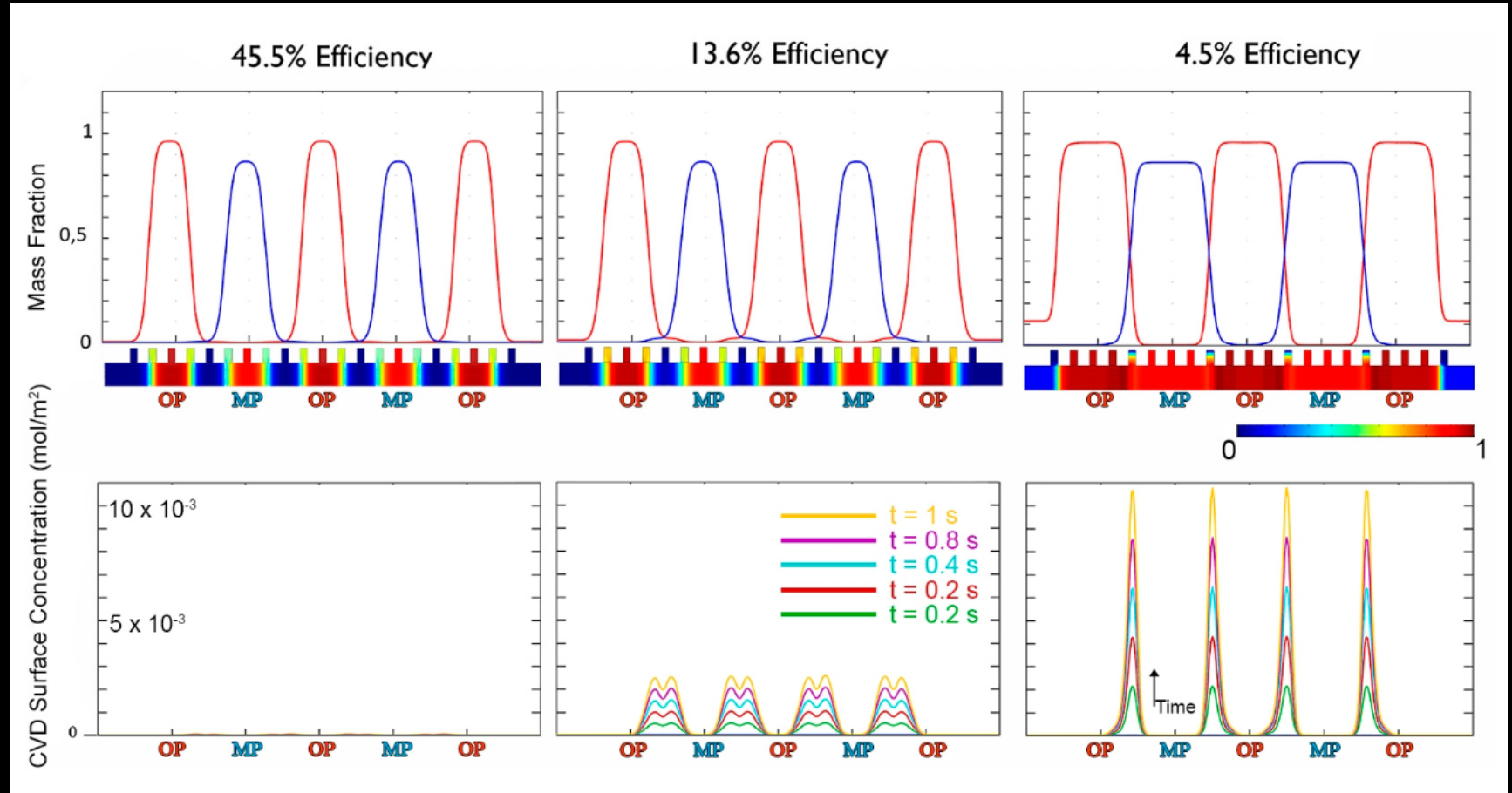
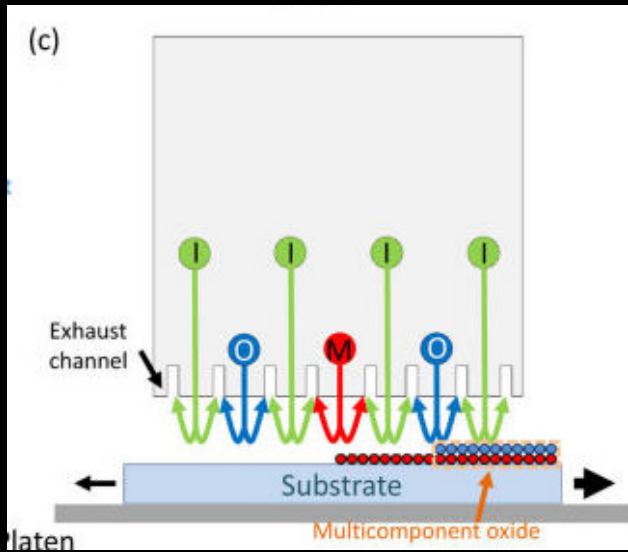


K. Musselman et al. *Nanoscale Horizons*, 2017, 2, 110

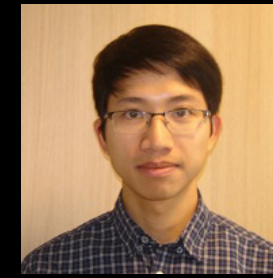
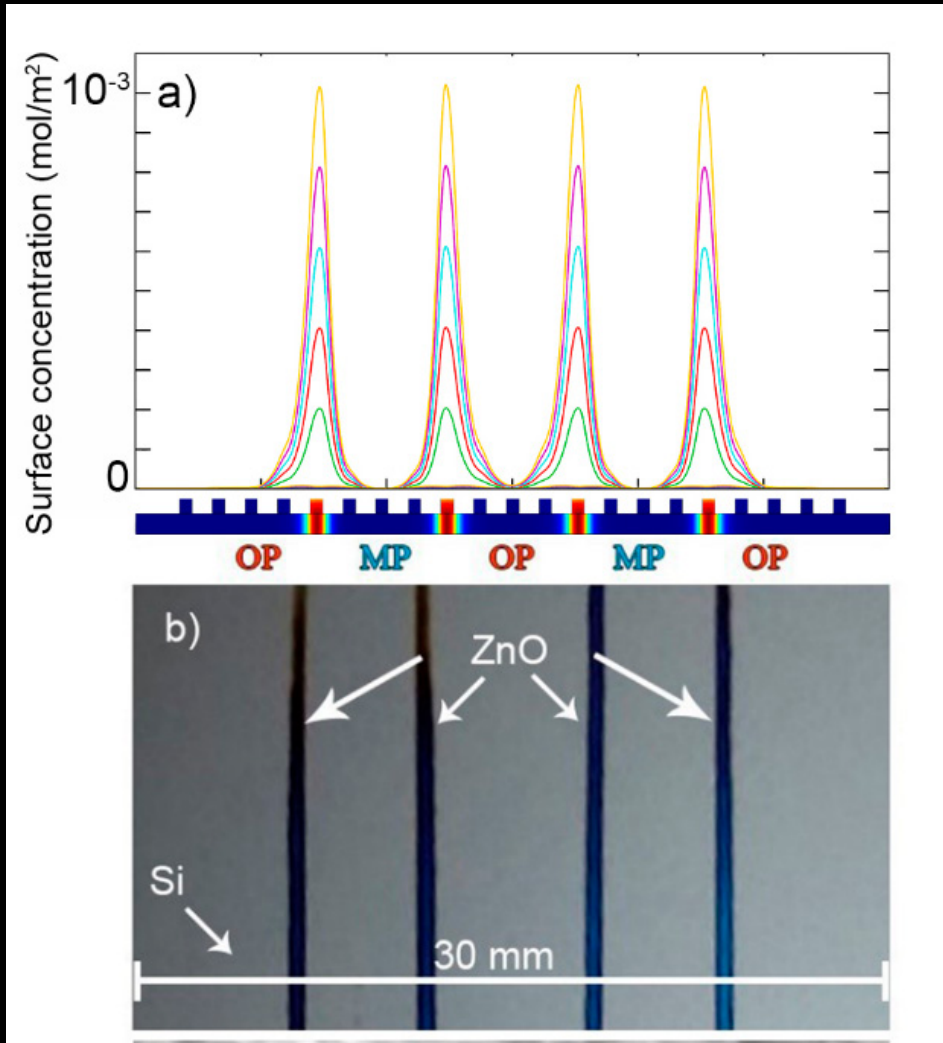


César Masse

- CFD simulations:



Static Deposition SCVD: an alternative approach to selective depostion



Viet Nguyen



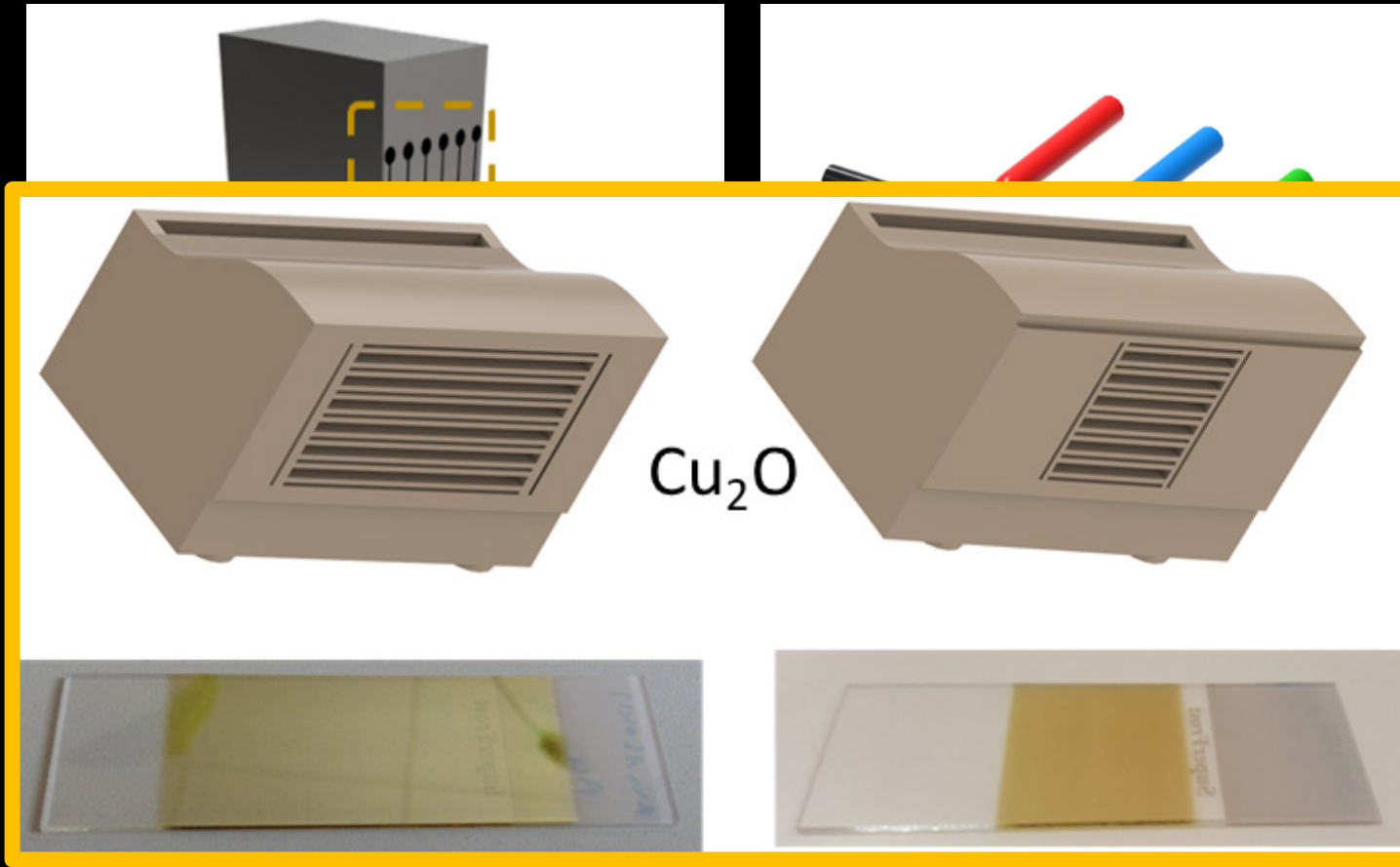
César Masse

- 3D printing for SALD heads:

Let's use 3D printing!



- 3D printing for ASD:



**César
Masse**



**Chiara
Crivello**



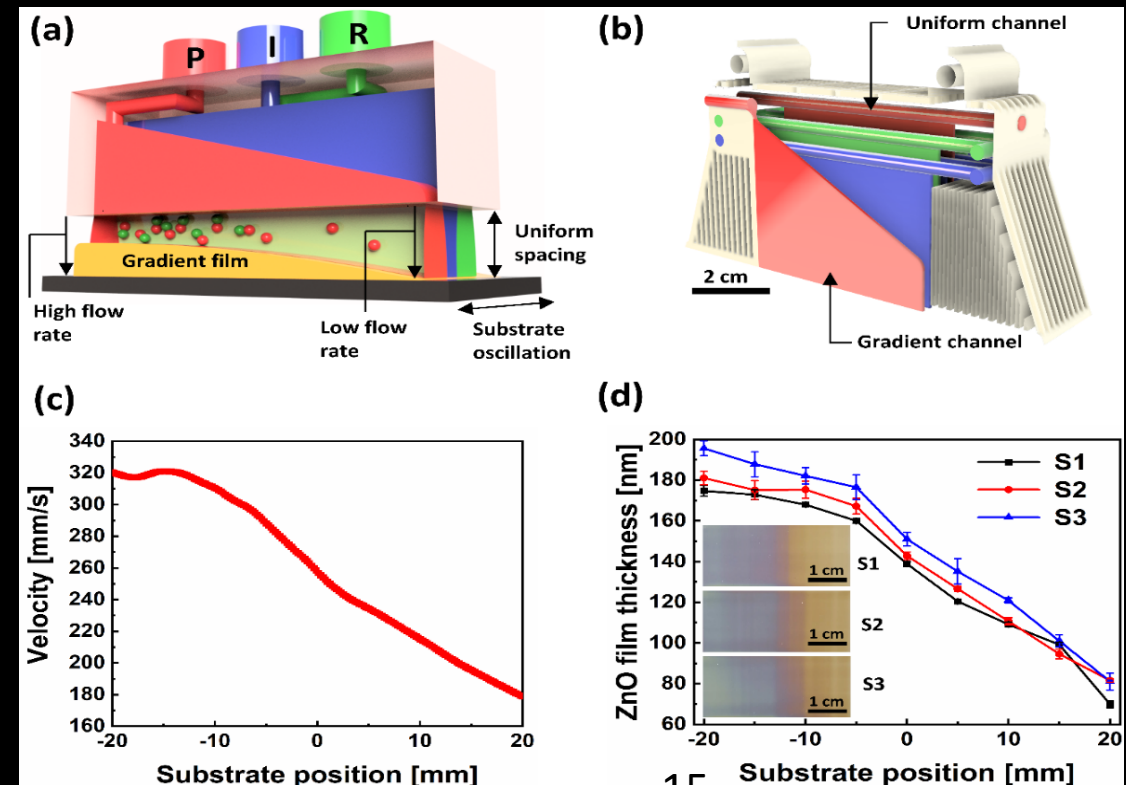
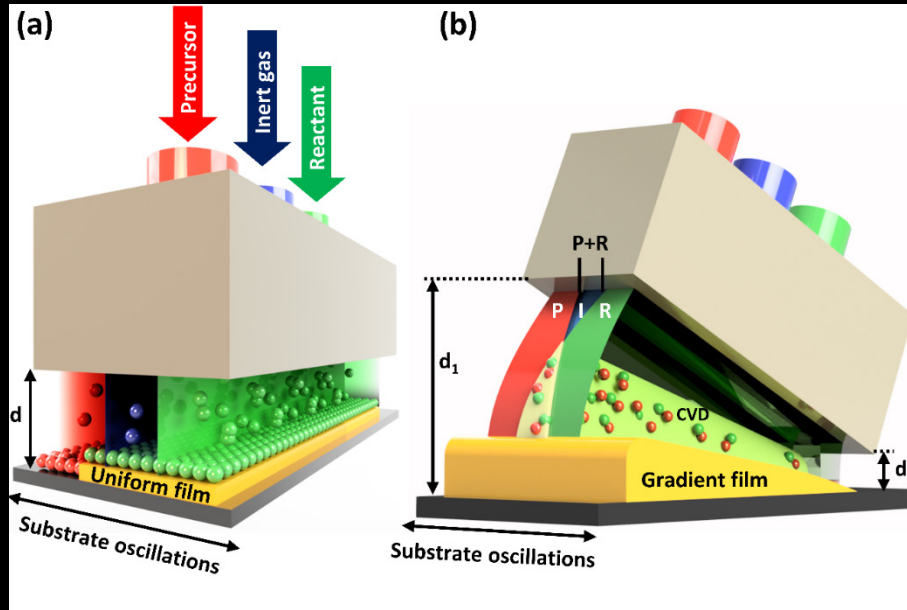
**Abdou
Sekkat**



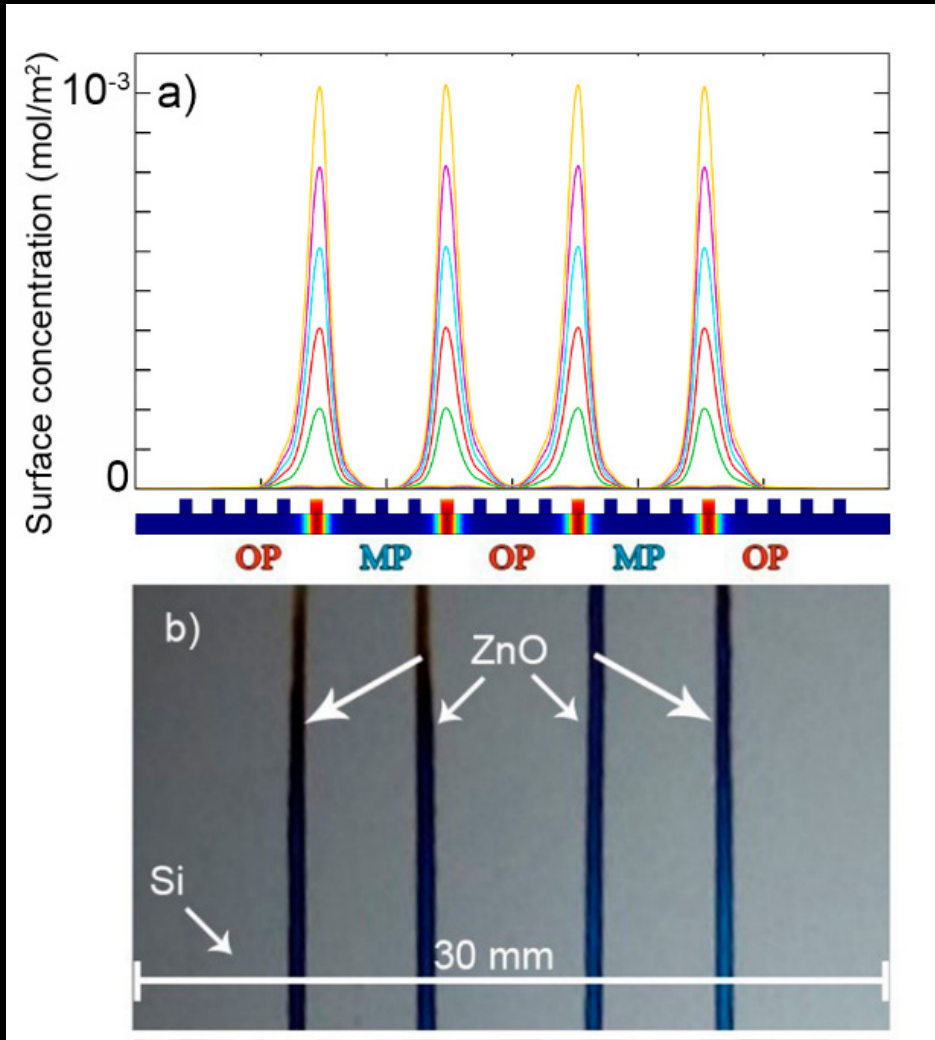
**Fidel
Toldrà**



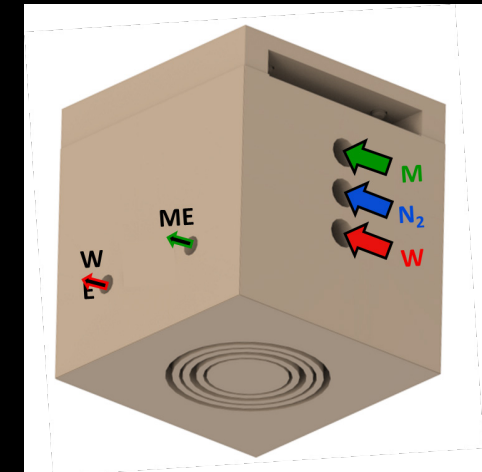
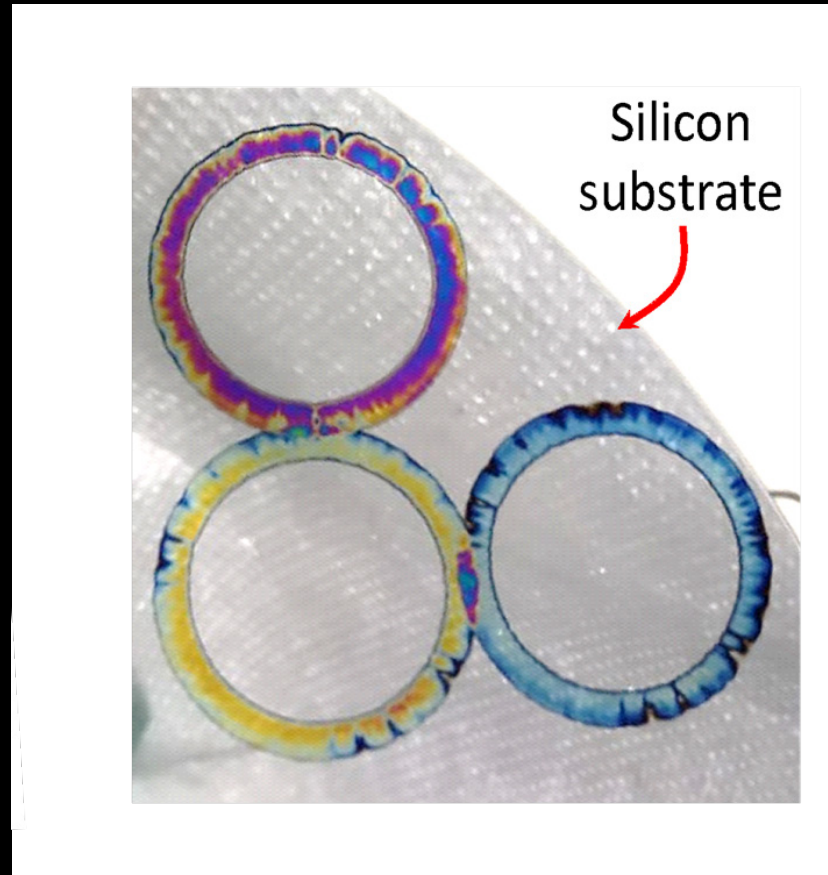
- non-homogeneous samples on purpose: thickness gradient*



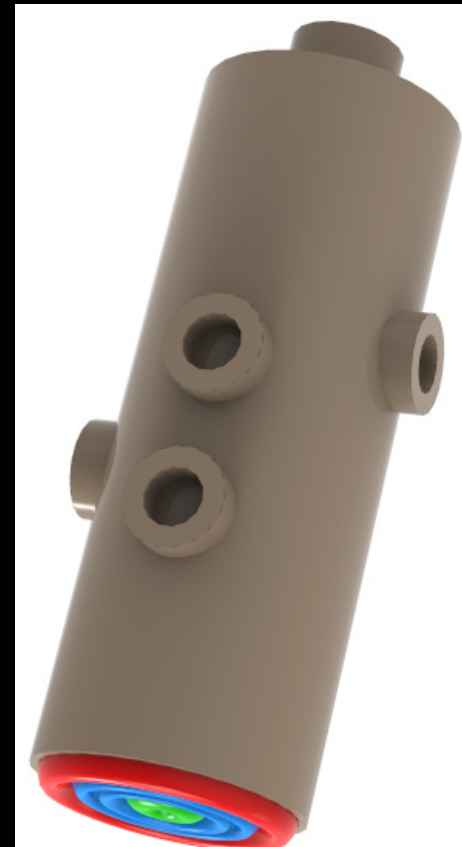
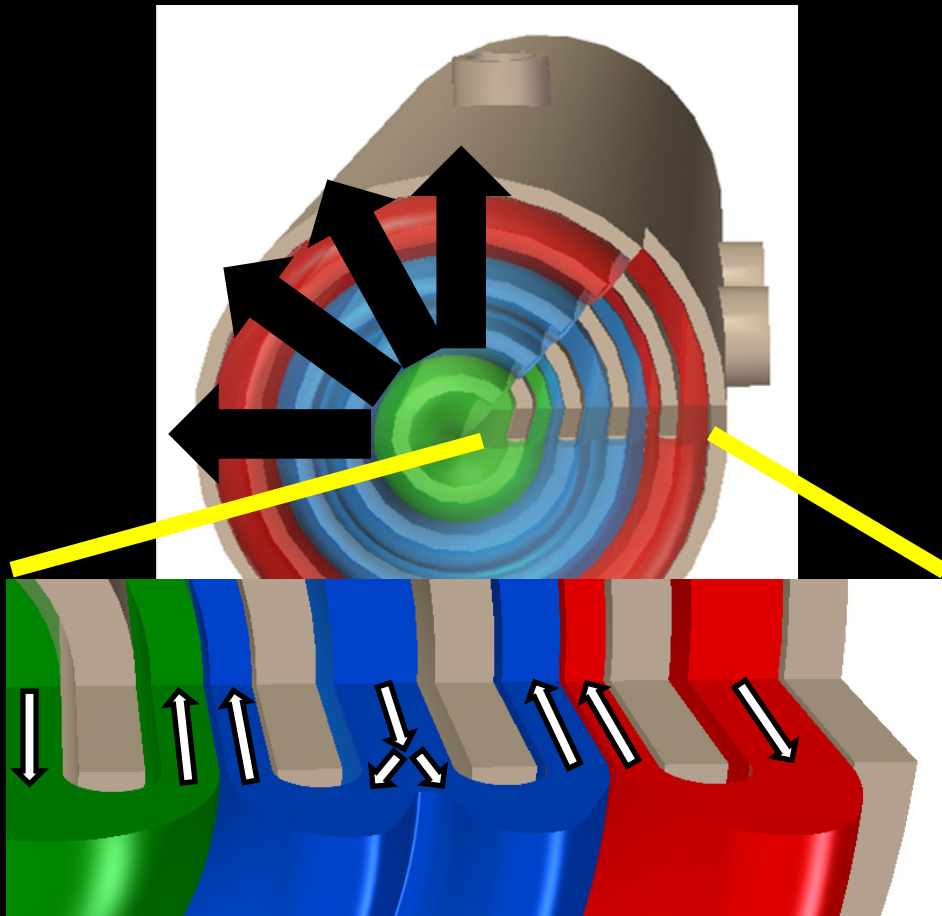
- 3D printed custom heads to be non-homogeneous (simulation)*



Static Deposition SCVD: an alternative approach to selective deposition

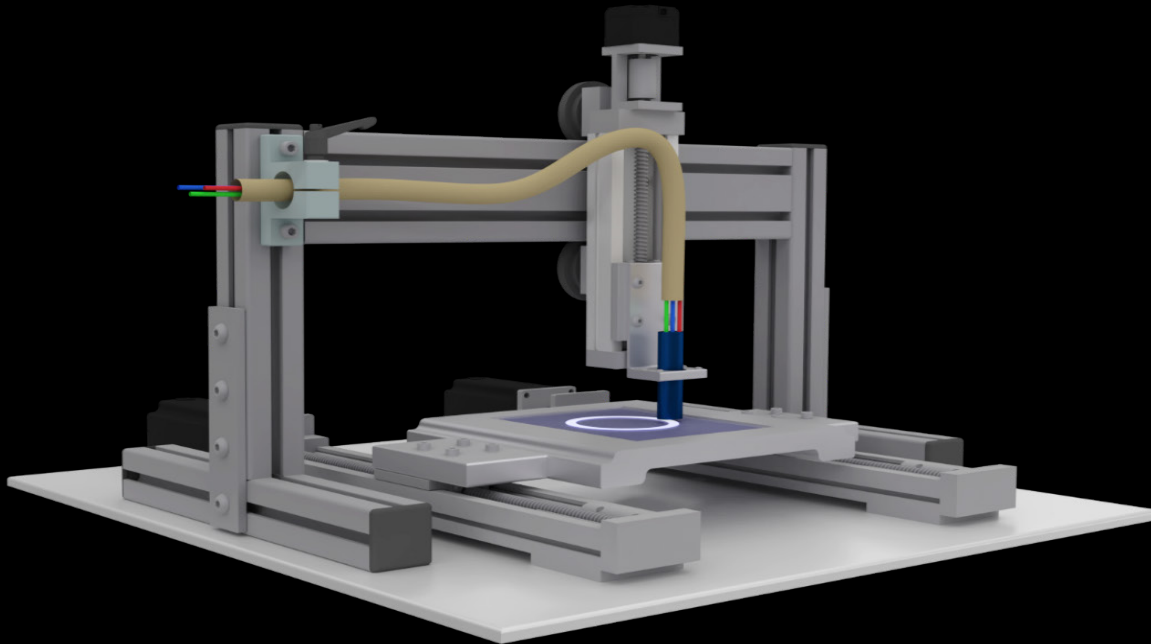


SALD PEN: Concentric channels. Possible to move in any direction



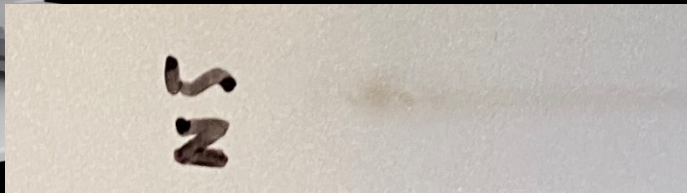
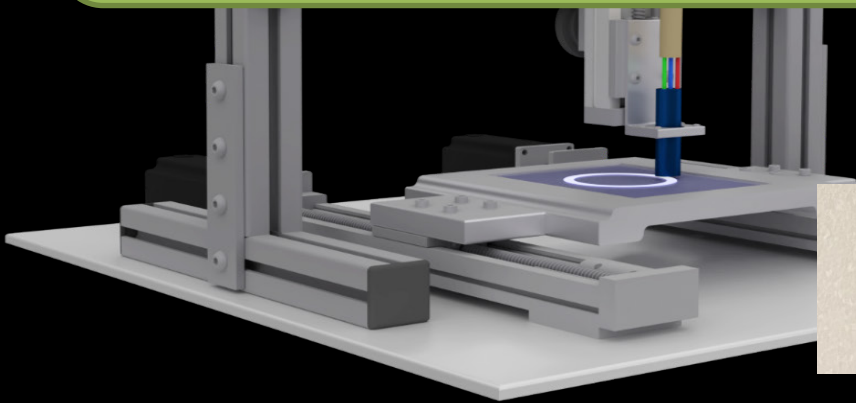
Masse de la Huerta, et al., Adv. Mater. Tech, 2020, 5 (12), 2000657

- **SALD PEN: Concentric channels. GAS-PHASE 3D printing of functional materials with nanometric resolution in Z**

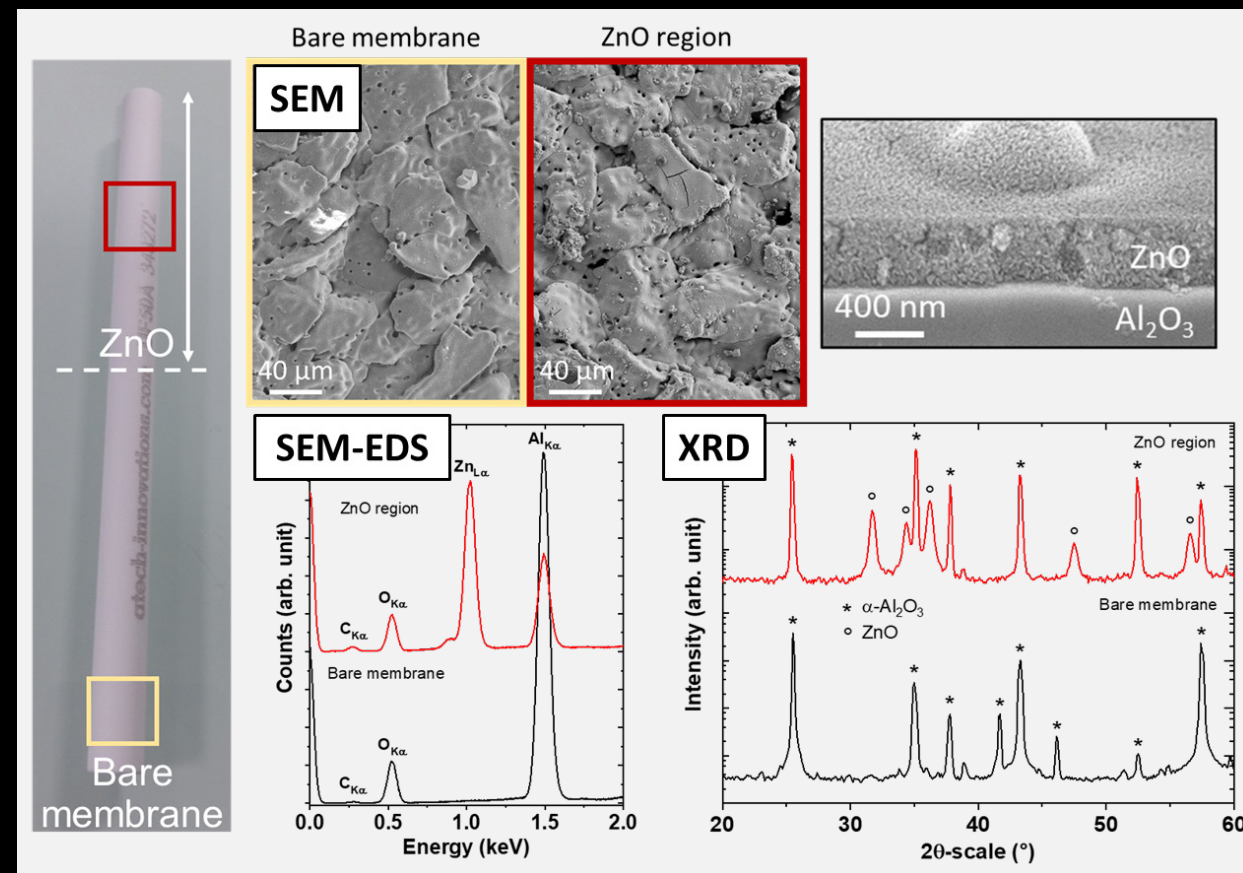
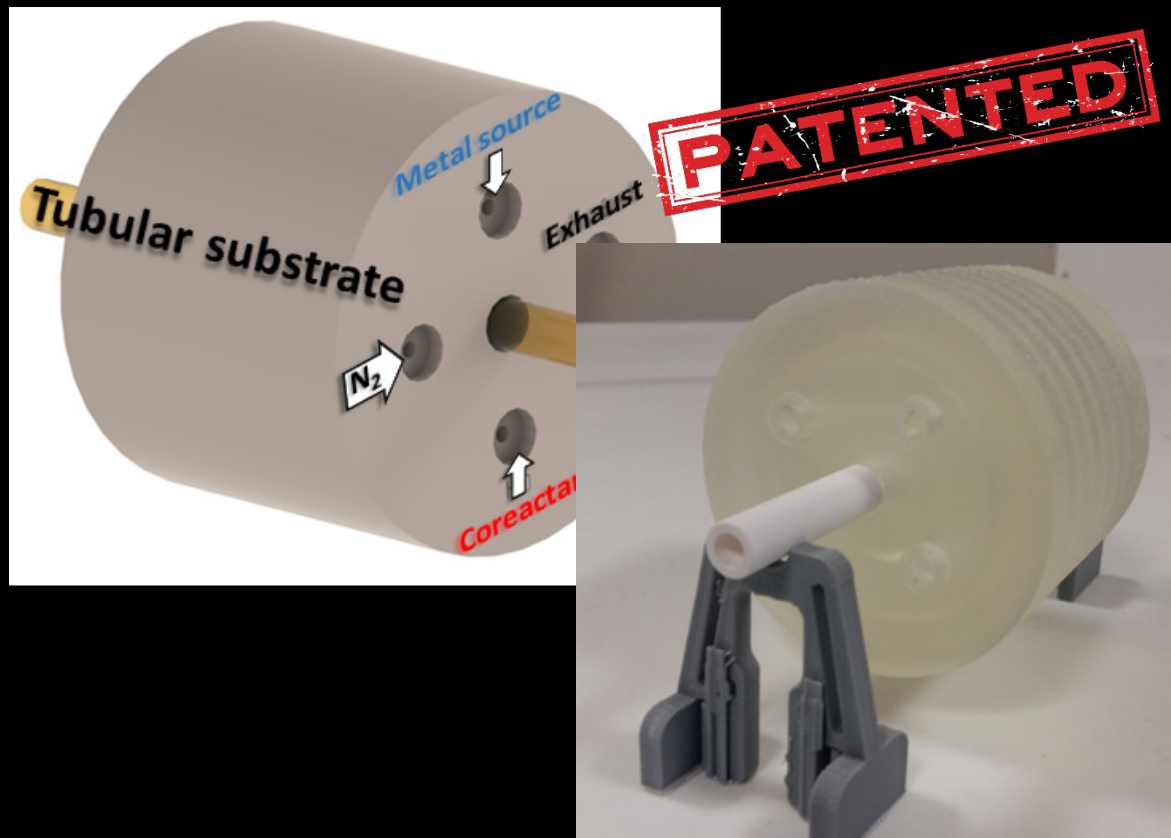


- **SALD PEN: Concentric channels. GAS-PHASE 3D printing of functional materials with nanometric resolution in Z**

New gas-phase 3D printing approach with nanometric resolution in Z



- Custom SALD close proximity head for tubular-cylindric substrates



SPECIFICATION OF THE SALD

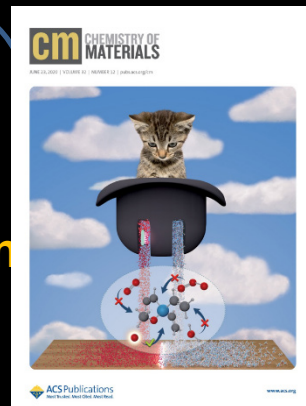
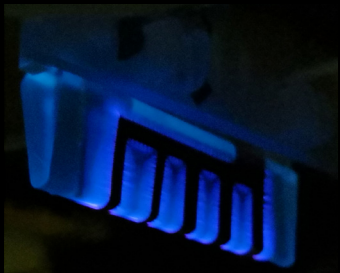
| | |
|------------------------------|--------------------------------|
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| Growth rate | Up to 2 nm/Cycle |
| Substrates | Metal, glass, plastic, tissue, |
| Maximum Achievable Thickness | Up to several μm |

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ZnO, Al₂O₃, Al:ZnO, Cu, Cu₂O, CuO, TiO₂, SiO_x, MgO, SnO₂, Ga₂O₃, HfO₂, Ag, CeO₂, ZrO₂, Hybrids (Metalcones, MOFs, ...)

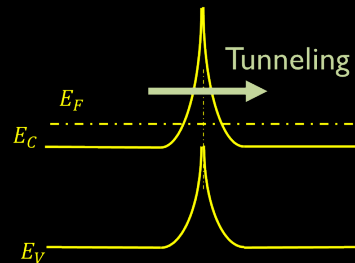
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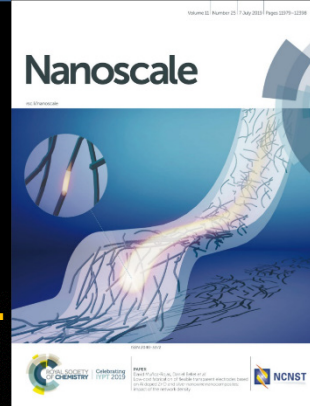
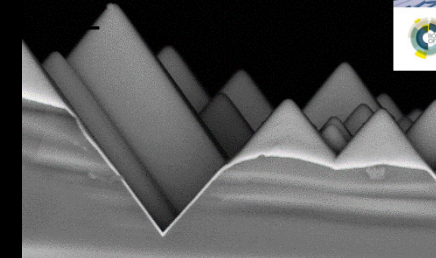
Fundamental studies

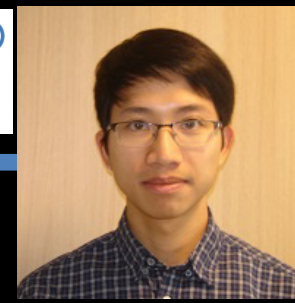
- Effect of open-air processing
- New materials



Applications

- TCM
- PV
- Sensors
- Res.Switc.





Viet Nguyen

Deposition of Al:ZnO, as Transparent Conductive Oxide (TCO)



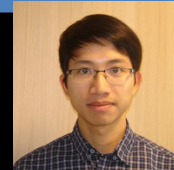
| Technique | T °C | t (nm) | μ (cm ² V ⁻¹ s ⁻¹) | N (cm ⁻³) | ρ (Ω cm) |
|-----------|------|--------|--|-----------------------|-----------------------|
| PLD | | | | | 10 ⁻⁵ |
| DC Sput | | | | | 10 ⁻⁴ |
| RF Sput | | | | | 10 ⁻⁴ |
| MOCVD | | | | | 10 ⁻⁴ |
| ALD | | | | | 10 ⁻³ |
| SALD-TNO | 200 | 320 | 5 | 5,0x10 ²⁰ | 2,0x10 ⁻³ |
| SALD-LMGP | 200 | 210 | 2,6 | 4,25x10 ²⁰ | 5.6x10 ⁻³ |

New theoretical model that takes into account tunneling through the GBs in highly degenerated semiconductors (TCO)

State-of-the-art, comparable to Tin-doped In oxide (ITO), standard TCO

Why such a low mobility??

ANR project DESPATCH, coll GREMI, LTM: Plasma deposition of SiO_2



Viet Nguyen

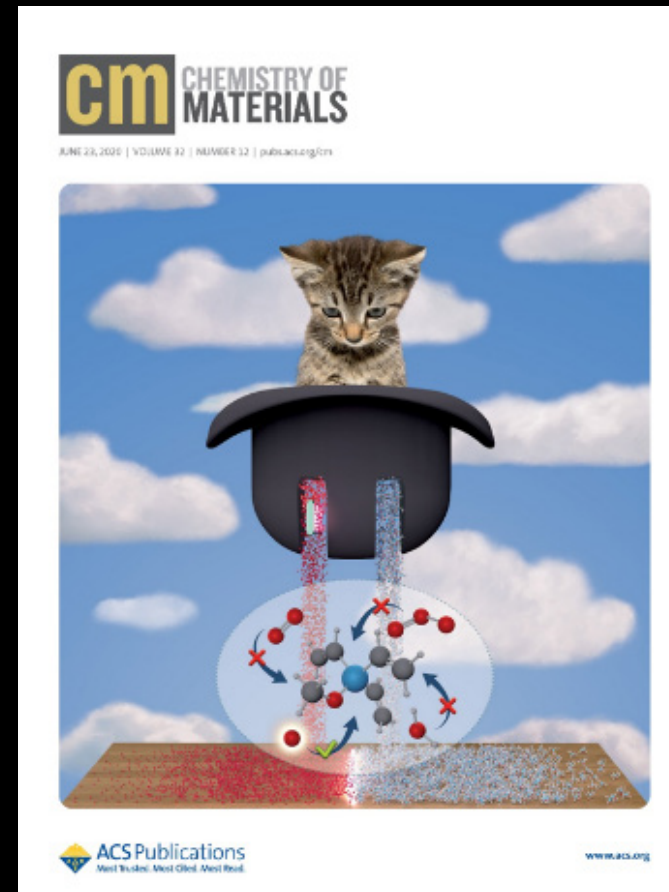
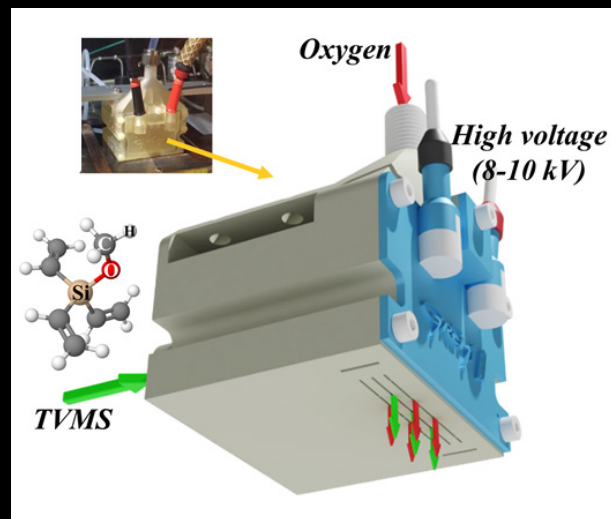
Direct Barrier Discharge (DBD)



Atmospheric

SiO_2 on Si
from RT to
150 °C

Integration in SALD head



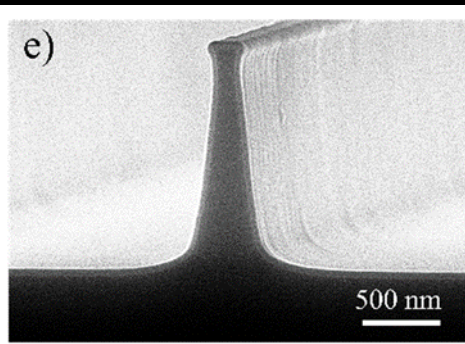
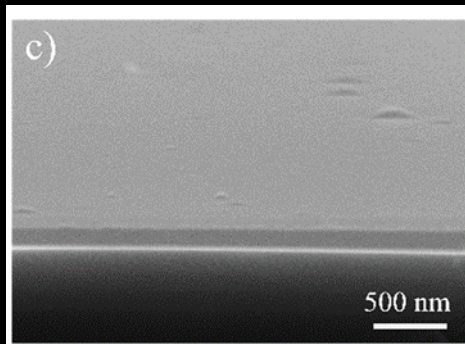
ANR project DESPATCH, coll GREMI, LTM: Plasma deposition of SiO₂

Direct Barrier Discharge (DBD)

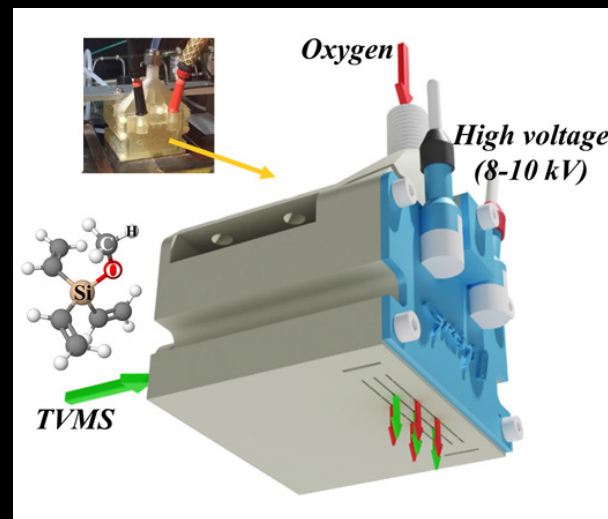


Atmospheric

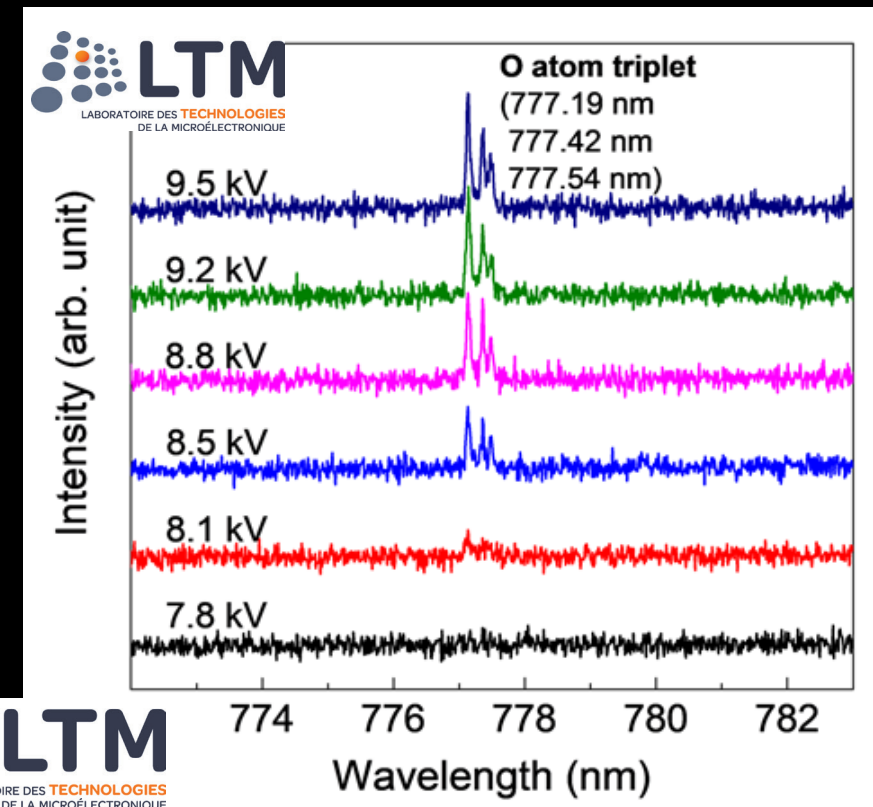
SiO₂ on Si
from RT to
150 °C



Integration in SALD head



Optical Emission Spectroscopy

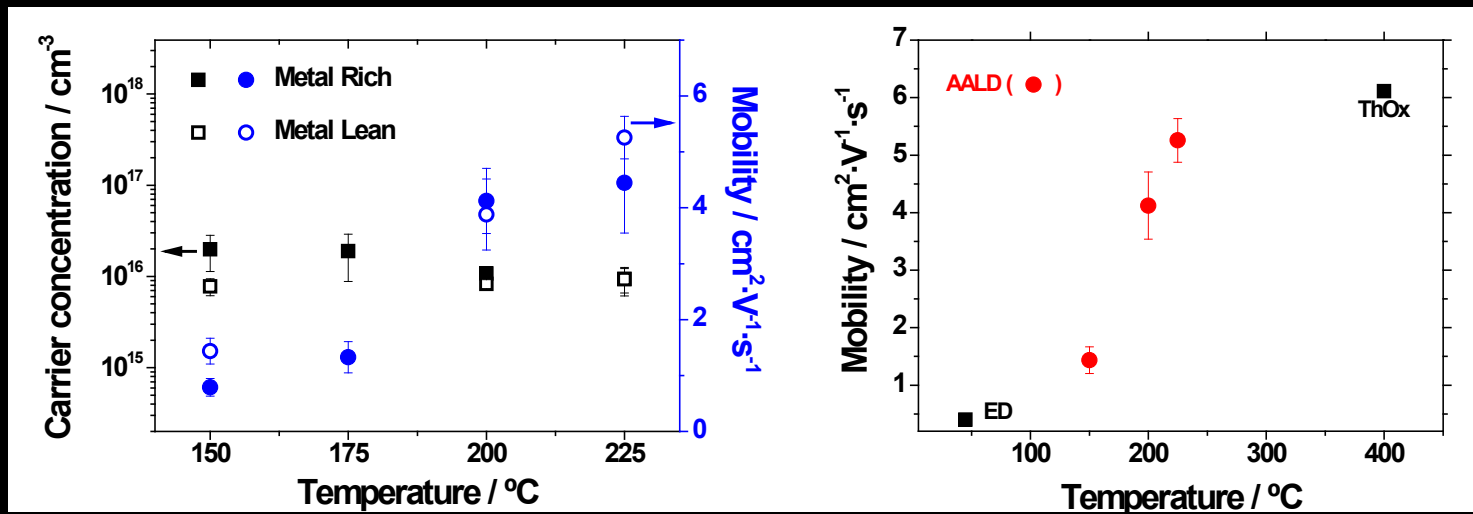
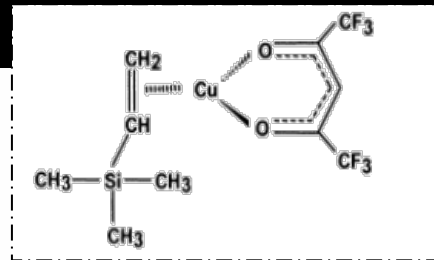
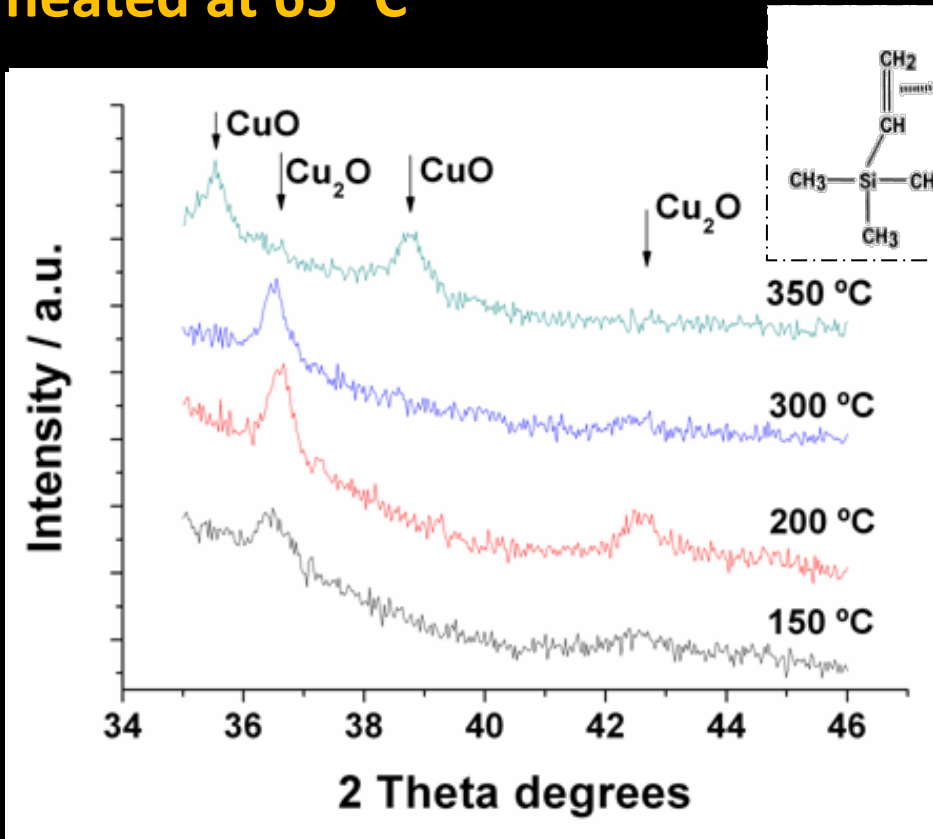


First SALD deposition of Cu_2O back in 2012

Cu_2O : abundant elem. Many applications
 Cupraselect ($\text{Cu}(\text{tmvs})(\text{hfac}), \text{Cu}^+$) + H_2O Prec.
 heated at 65°C



Very good transport prop. **NO CLUE WHY. Non-stable precursor!!**

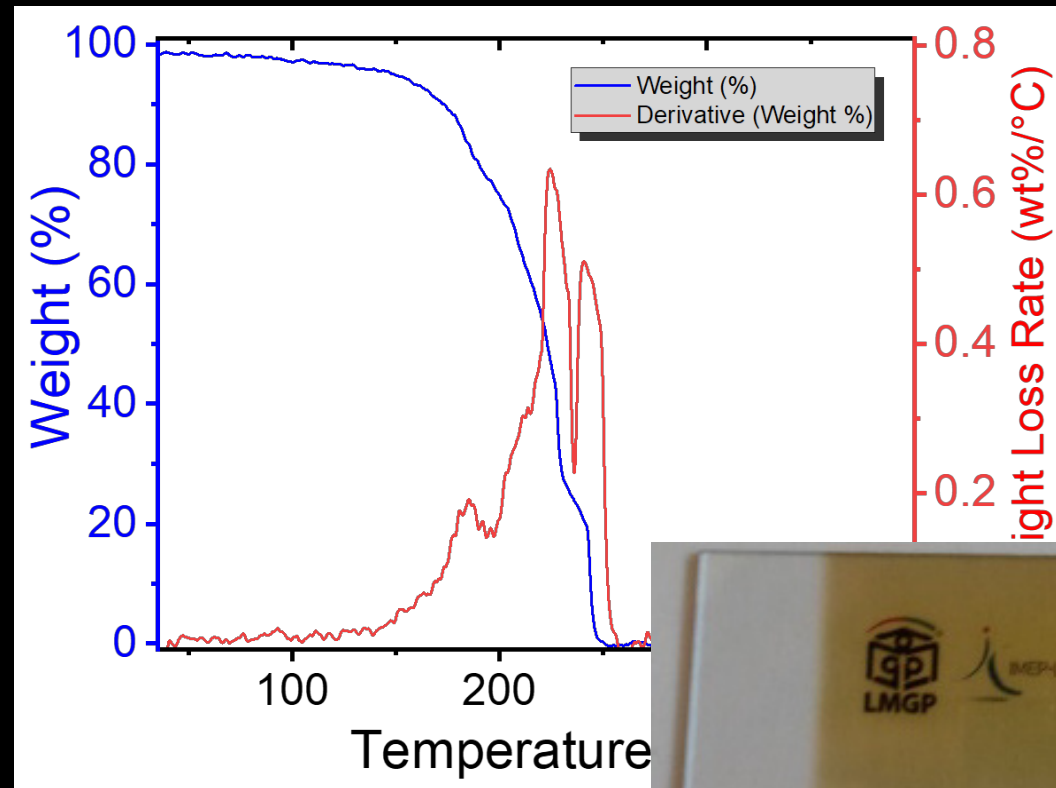
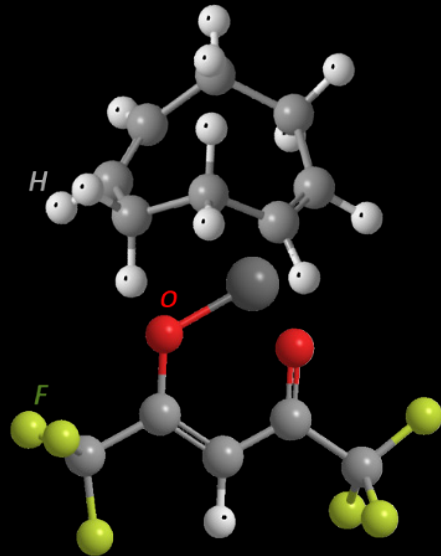
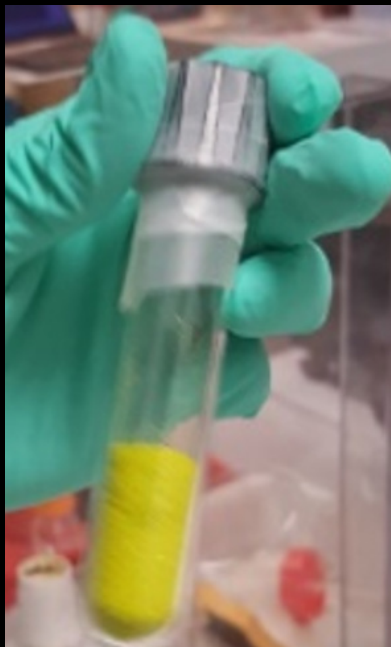




Abdou Sekkat

IDEX CDP project Eco-SESA: Cu₂O for all-oxide solar cells/harvesters

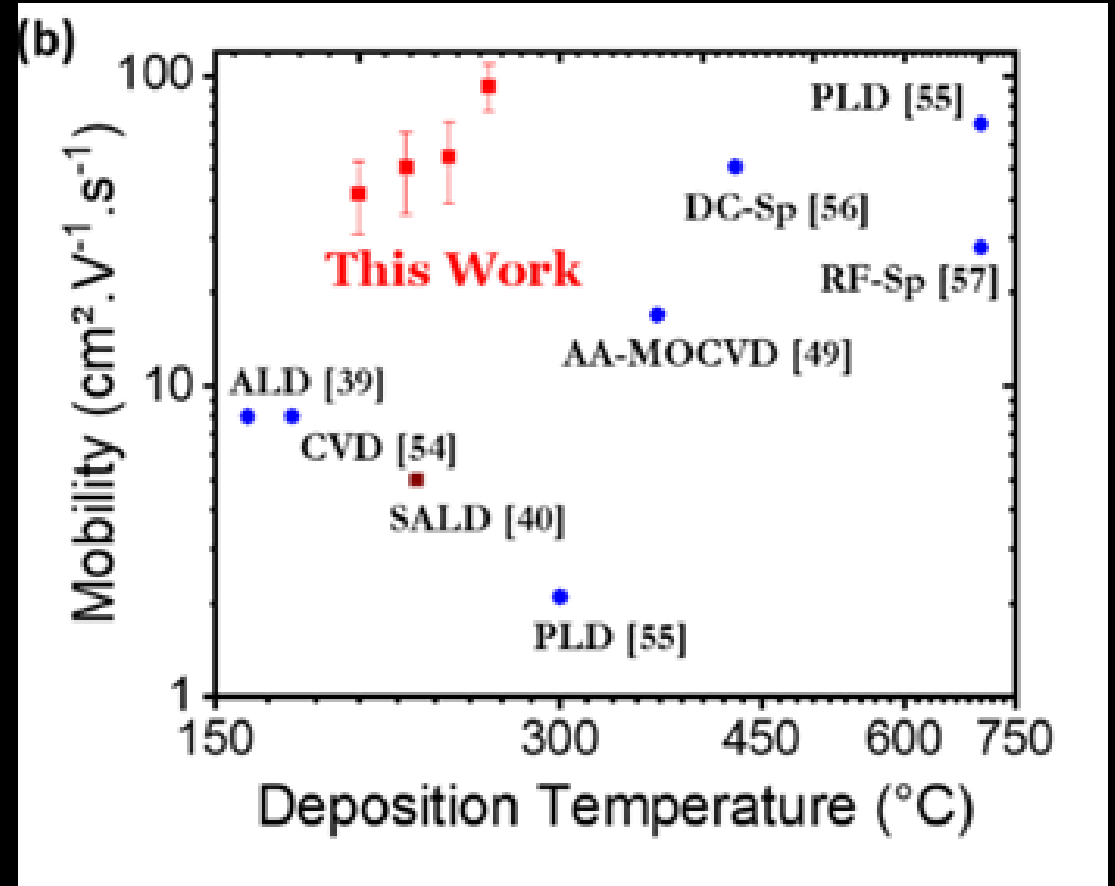
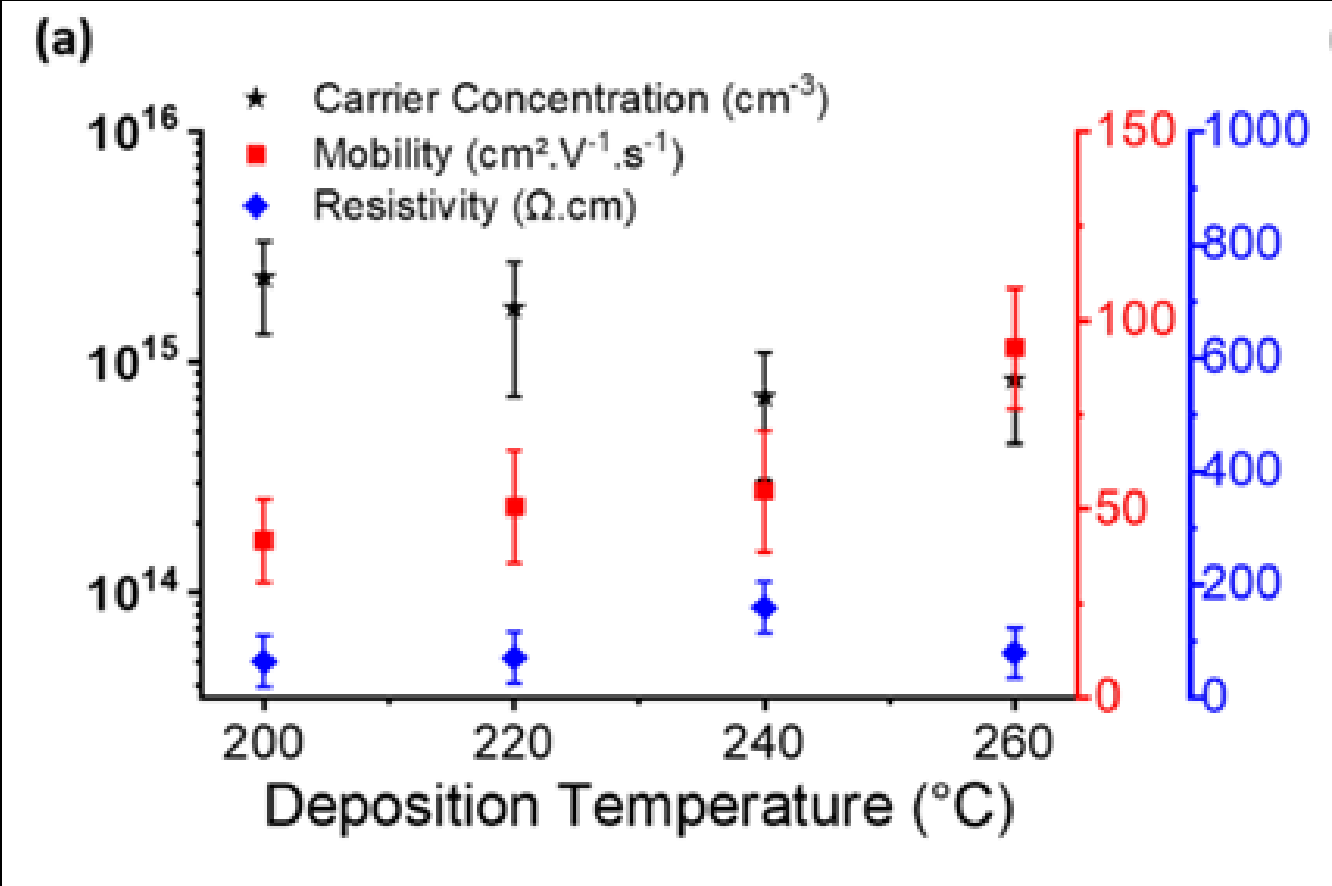
Cu₂O, abundant & non-toxic, many applications: transparent electronics



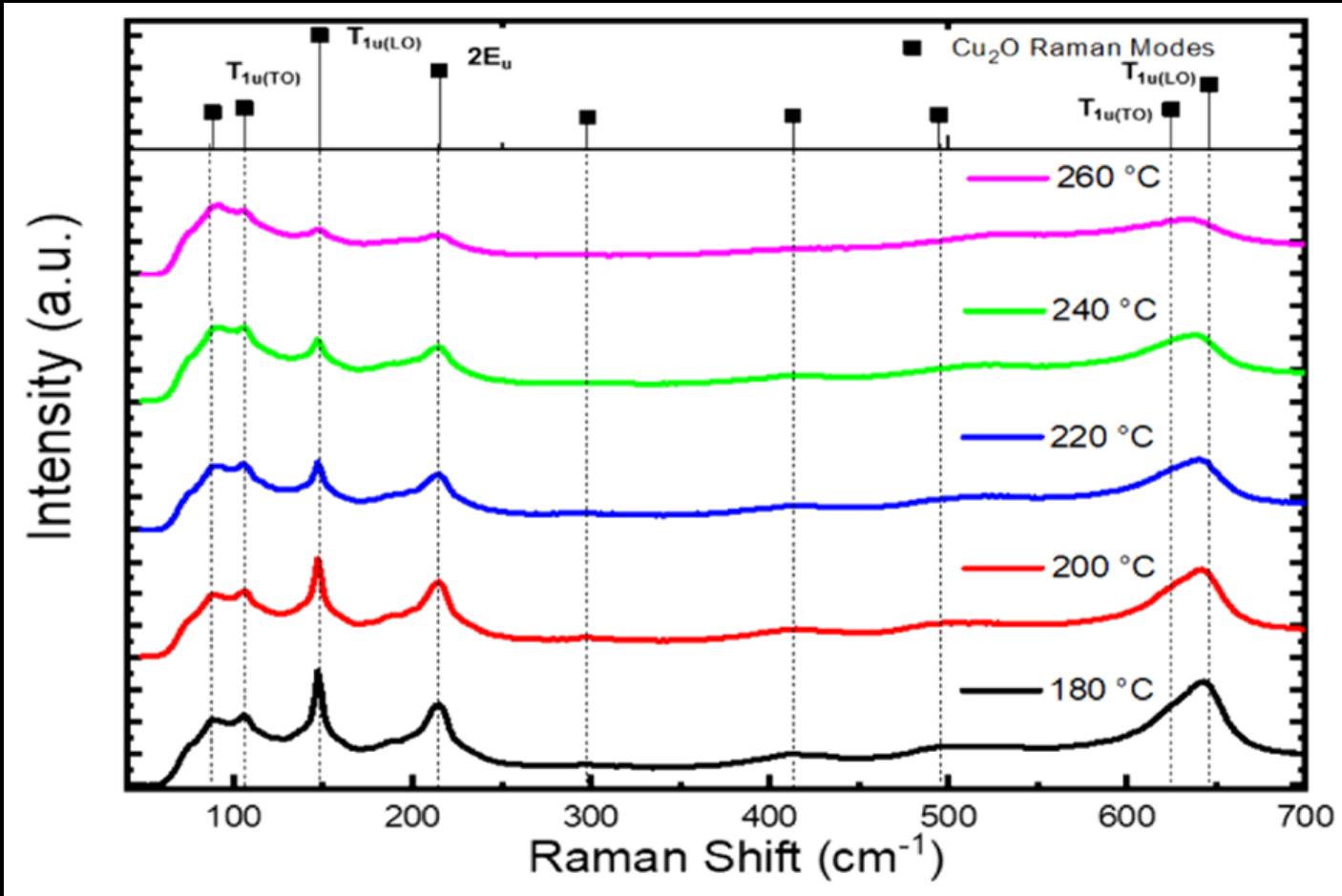
Solid Precursor, never used for CVD, ALD of Cu₂O: Cu(cod)(hfac), Cu⁺

Transport properties

Record mobility values! Close to SC Cu₂O. 10 times less charge concentration than with Cu(tmvs)(hfac)



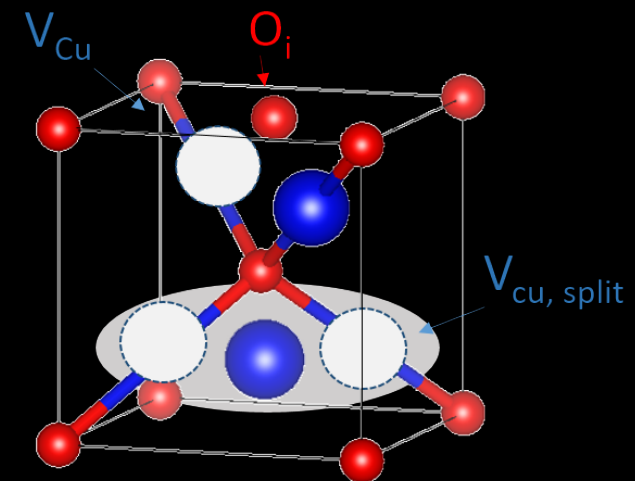
Raman comes to the rescue!!



Sander, T et Al (2014).

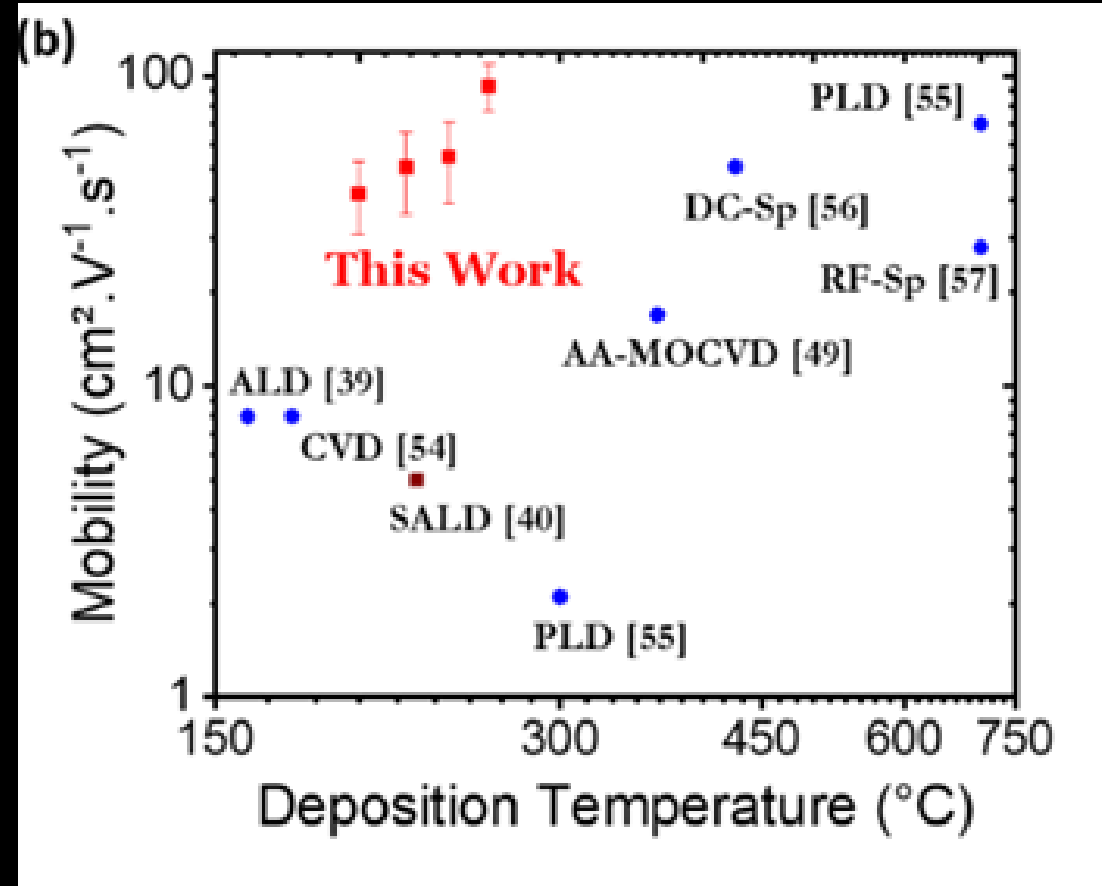
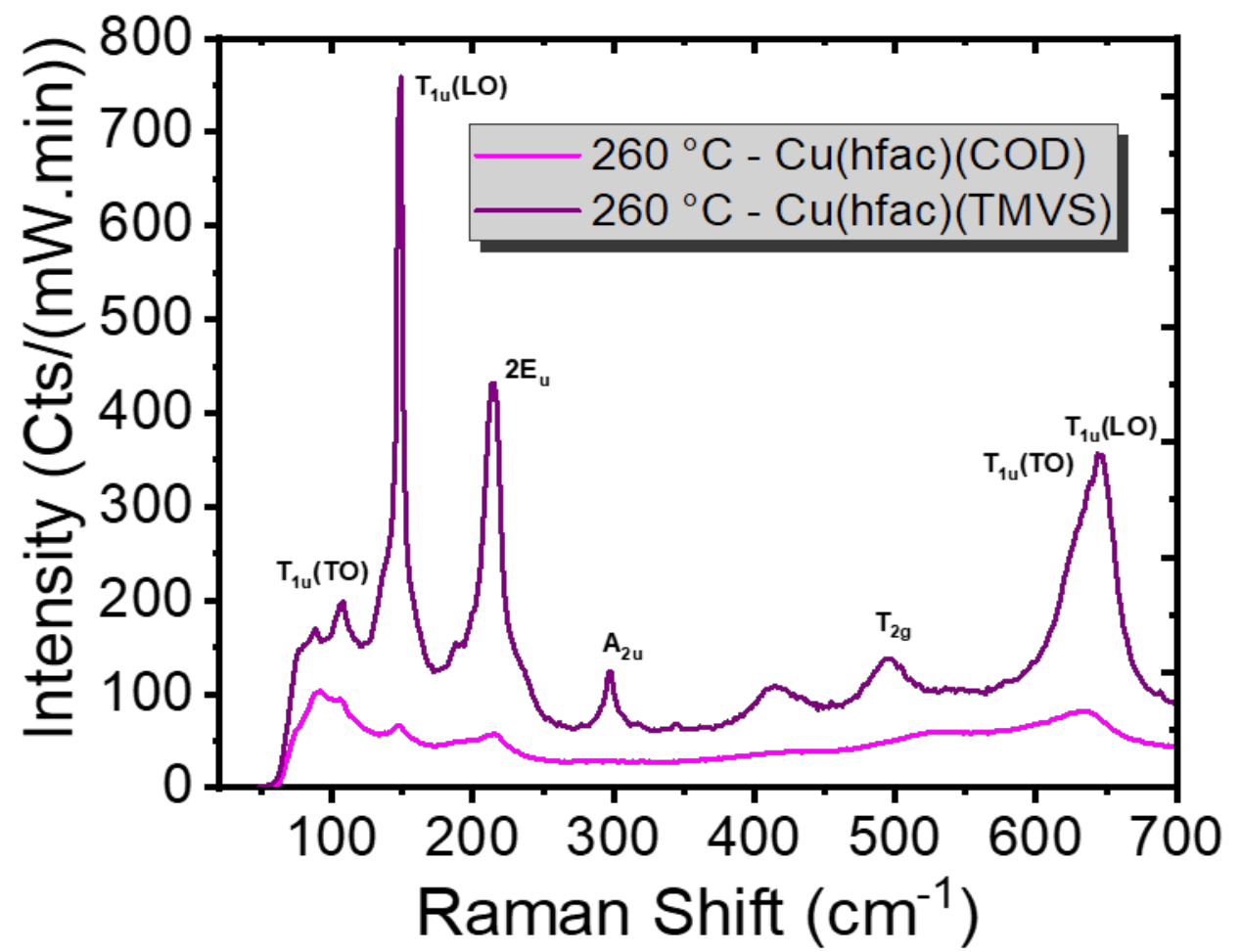
Physical Review B, 90(4).

The T_{1u} modes measured around 150 and 645 cm^{-1} correspond to phonons not at the zone center: they are activated by defect namely V_{Cu} , $V_{\text{Cu,split}}$ and O_i

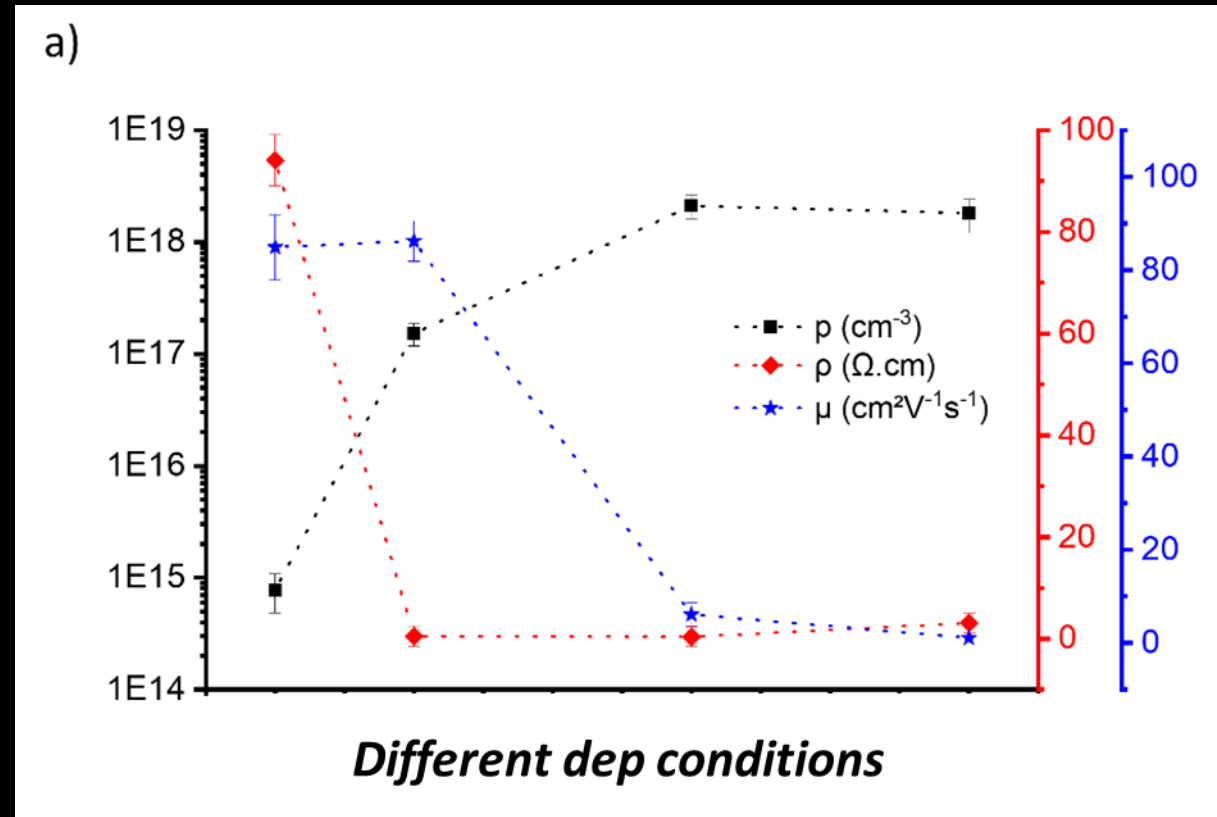
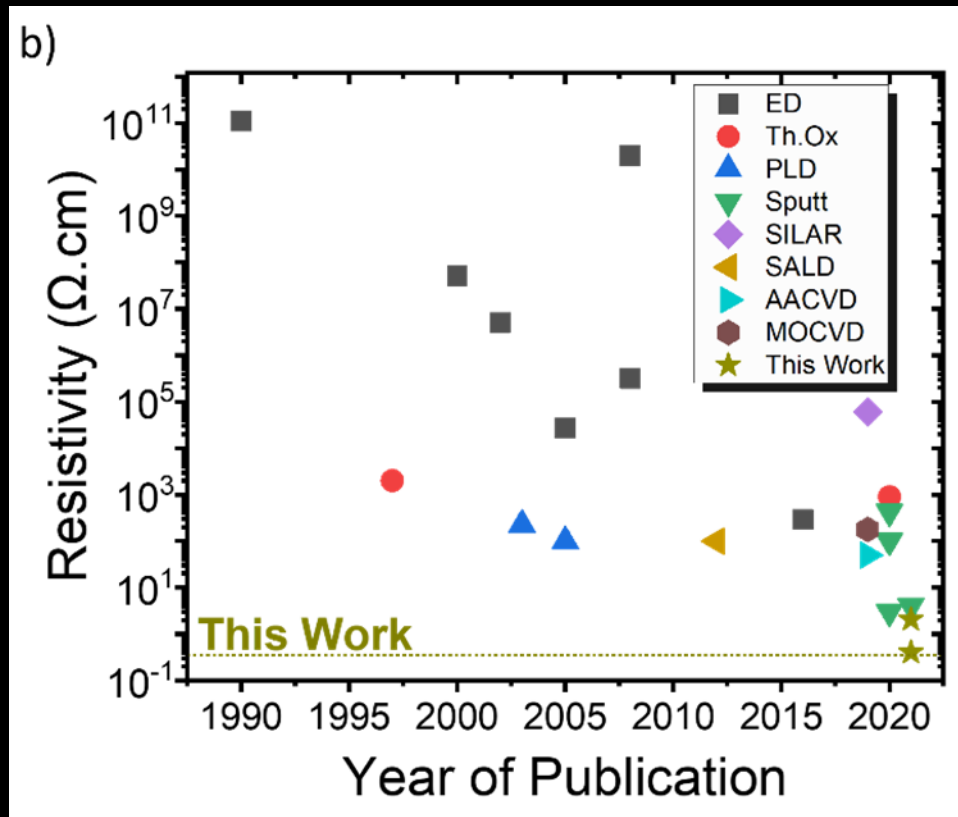


Transport properties

Strong effect of temperature and precursor used on the amount of defects (copper vacancies)

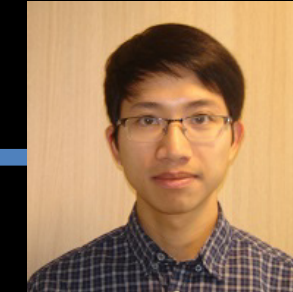


Even Further optimized, to be published



Record resistivity value for non epitaxial Cu₂O thin films,
tunable transport properties

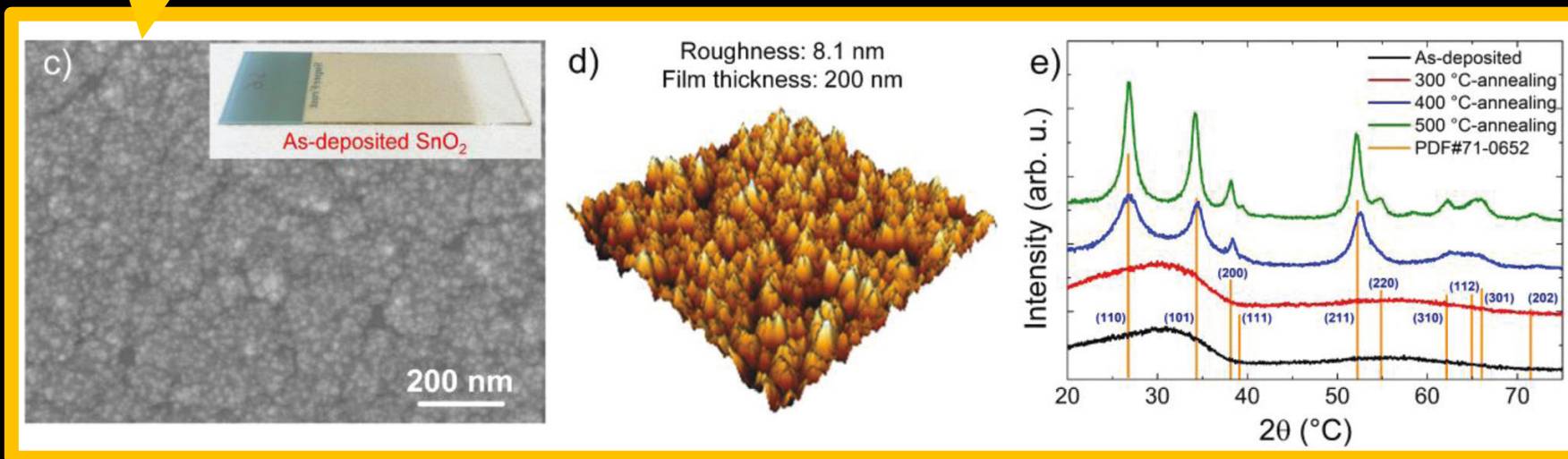
A. Sekkat, submitted



Masoud Akbari Viet Nguyen

Different Sn precursors evaluated (DFT) and some tested:

Sn(acac)₂ and bis[bis(trimethylsilyl) amino] tin(II)



Hydrophobic surface due to ligand adsorption : NO SnO₂ deposition

First demonstration of SALD deposition of SnO₂ from Sn(acac)₂, Key impact of open air processing and atm. Pressure on reaction output

SPECIFICATION OF THE SALD

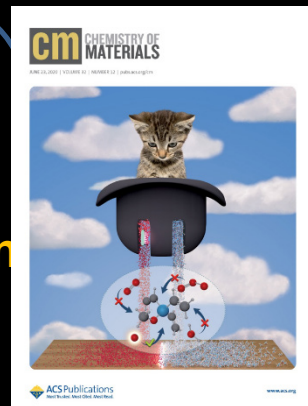
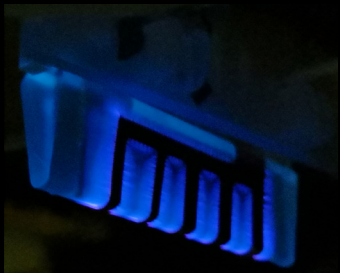
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| Deposition Temperature | RT to 350 °C |
| Deposition Area | 1 to 25 cm ² |
| Growth rate | Up to 2 nm/Cycle |
| Substrates | Metal, glass, plastic, tissue, |
| Maximum Achievable Thickness | Up to several μm |

Materials available or in study:

ZnO, Al₂O₃, Al:ZnO, Cu, Cu₂O, CuO, TiO₂, SiO_x, MgO, SnO₂, Ga₂O₃, HfO₂, Ag, CeO₂, ZrO₂, Hybrids (Metalcones, MOFs, ...)

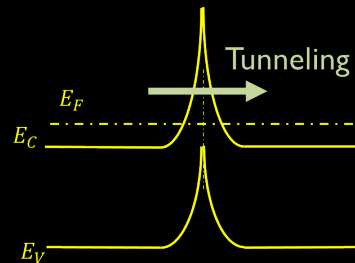
Design & Optimization

- Atm. Plasma activation
- up-scaling/simulation



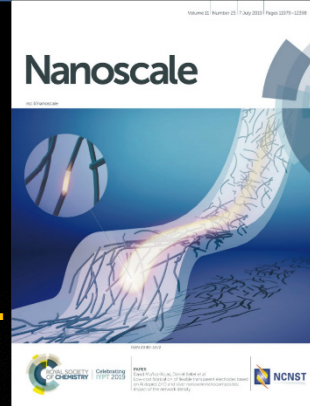
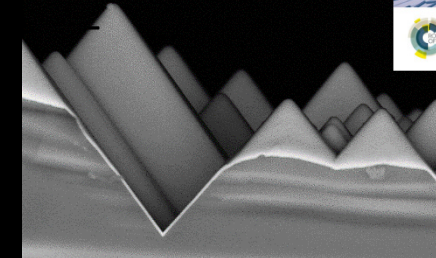
Fundamental studies

- Effect of open-air processing
- New materials



Applications

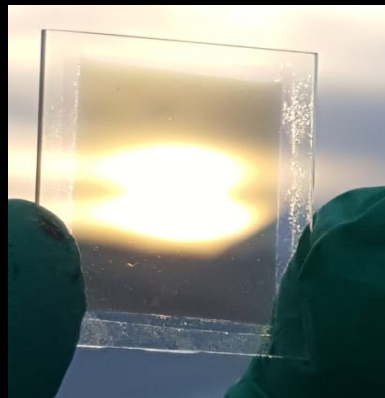
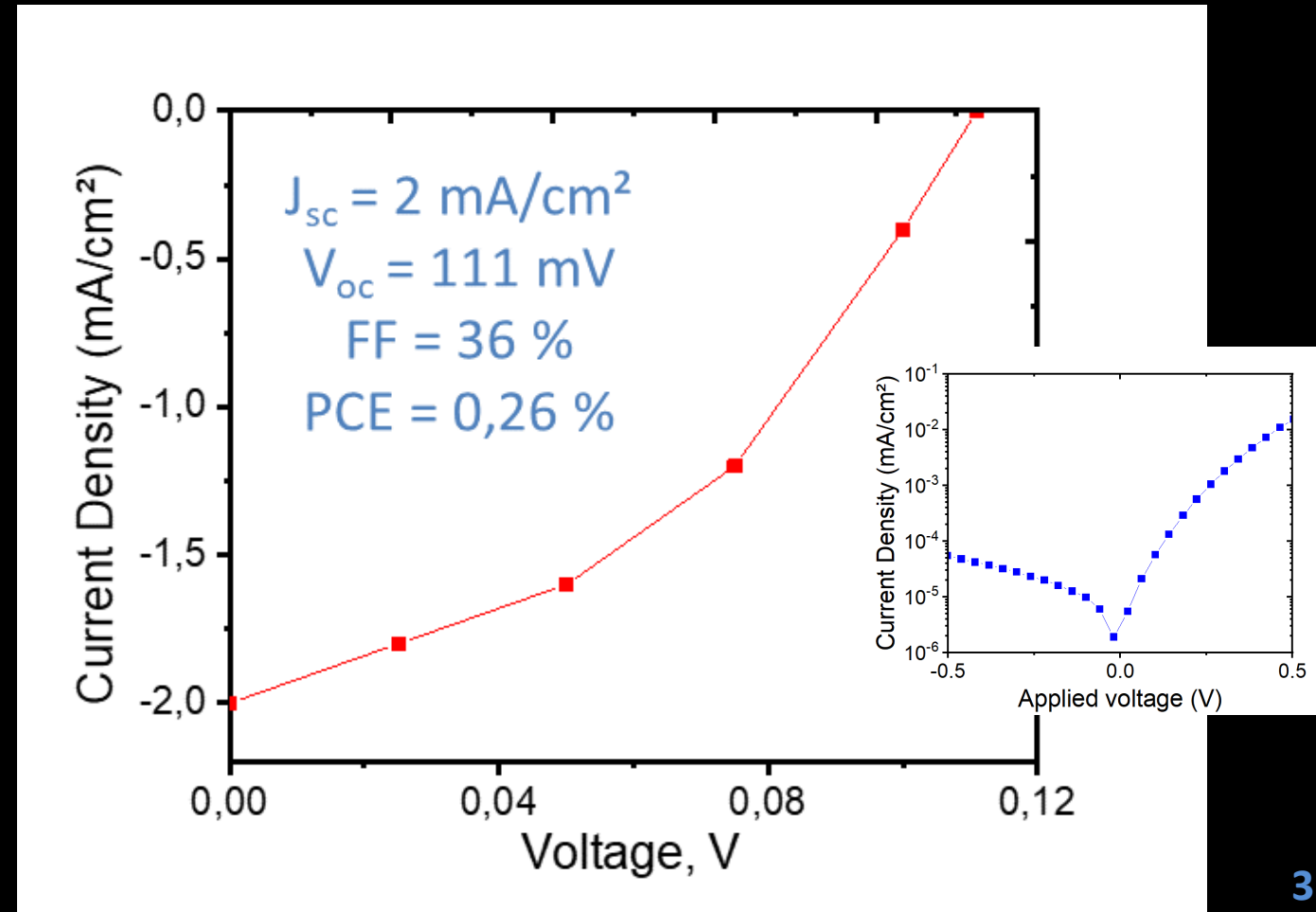
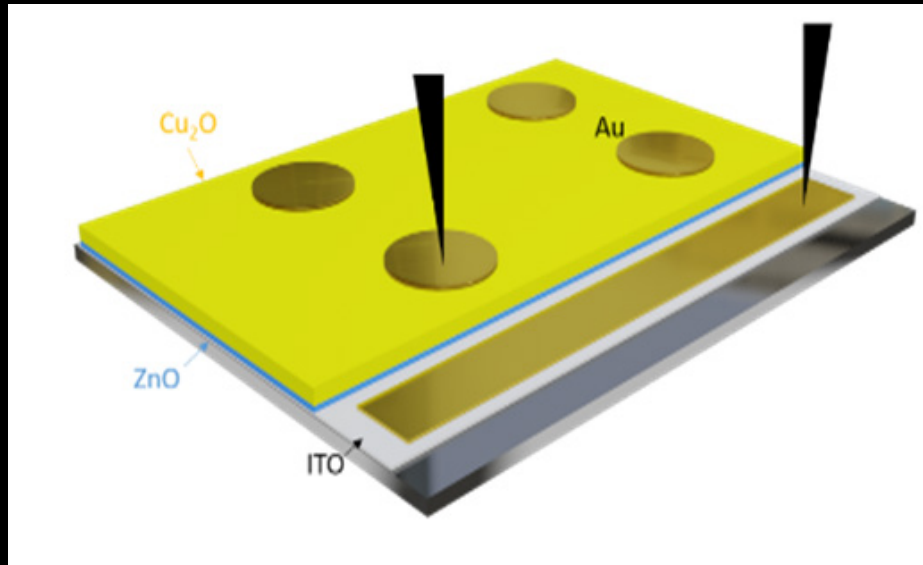
- TCM
- PV
- Sensors
- Res.Switc.



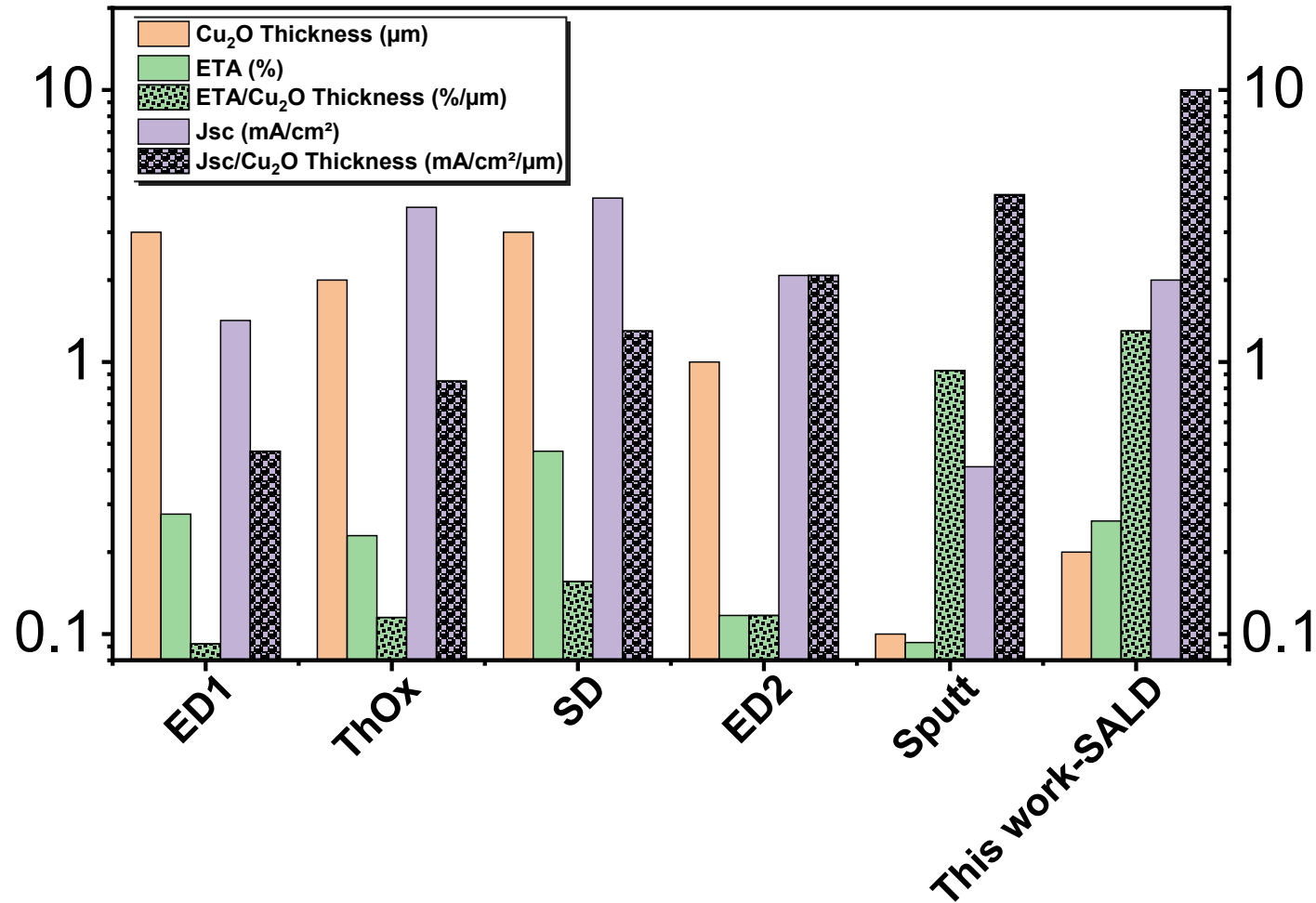


Abdou Sekkat

Ultra-thin ZnO/Cu₂O by SALD at low temperature

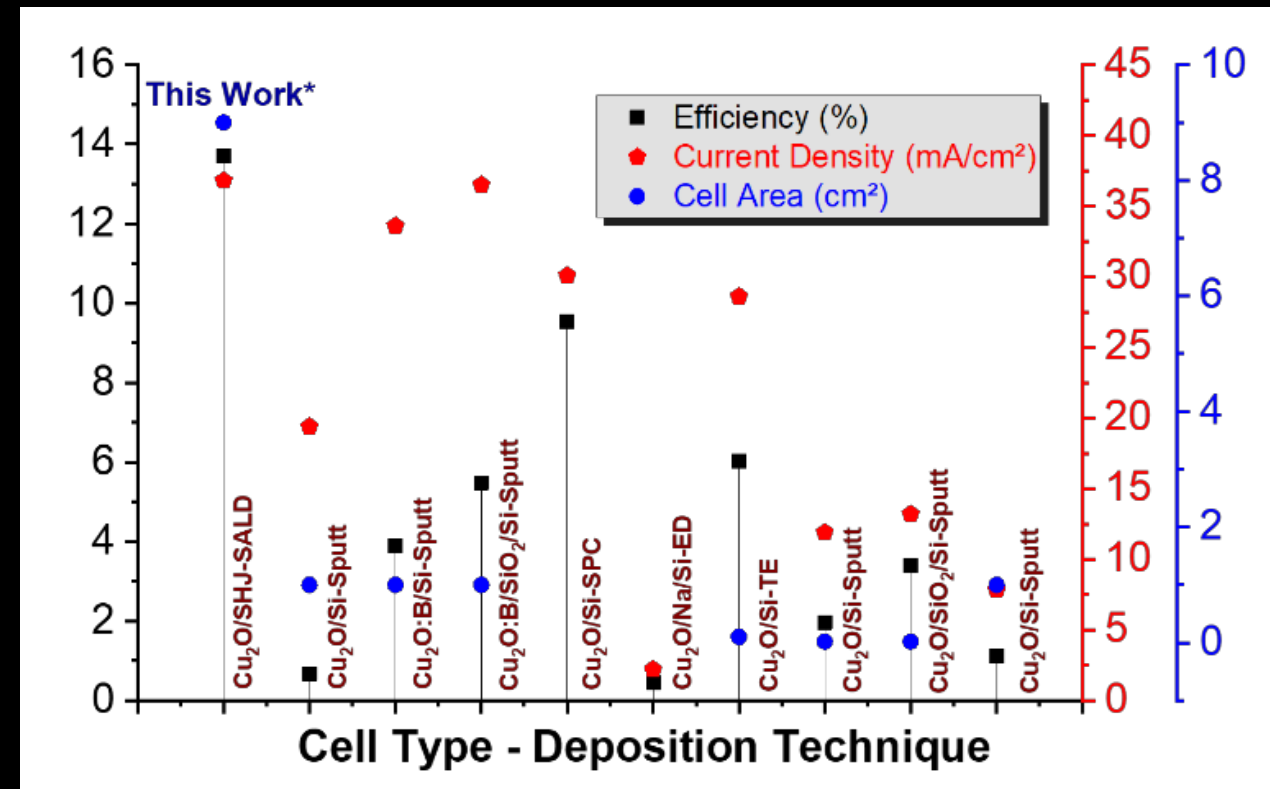
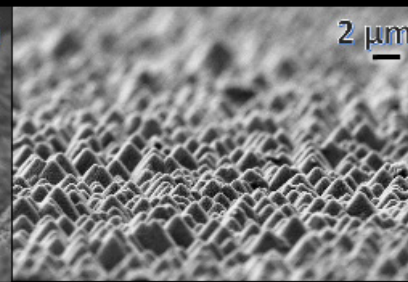
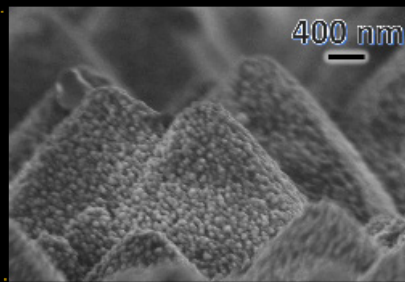
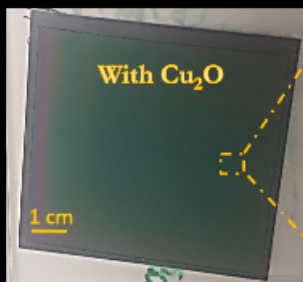
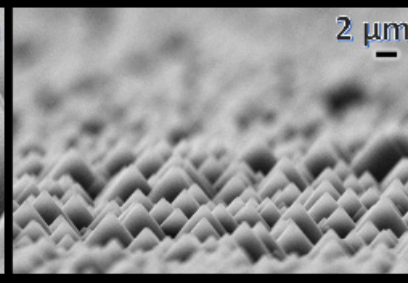
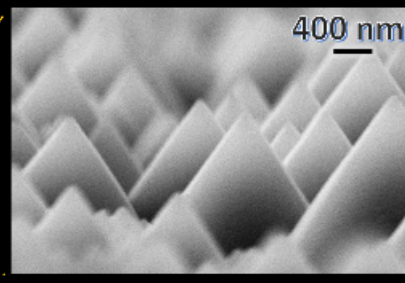
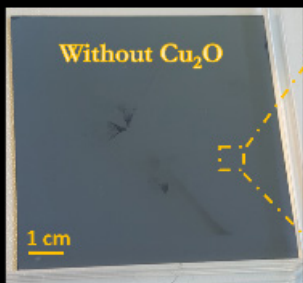
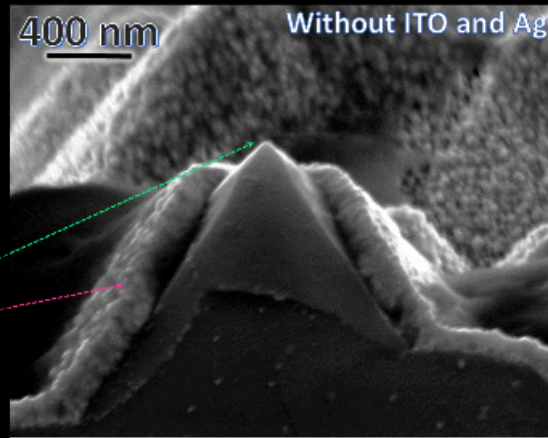
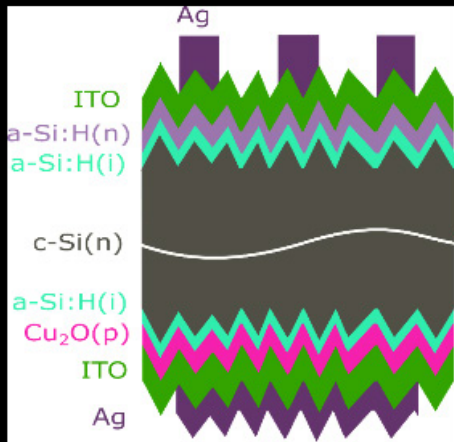


Ultra-thin ZnO/Cu₂O by SALD at low temperature



Atmospheric, low-temp. Fabrication of semitransparent Cu₂O devices with efficiency comparable to much thicker devices

Cu₂O for HET cells, coll INES



SPECIFICATION OF THE SALD

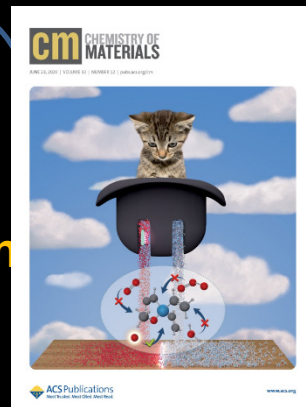
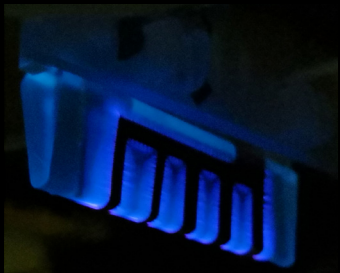
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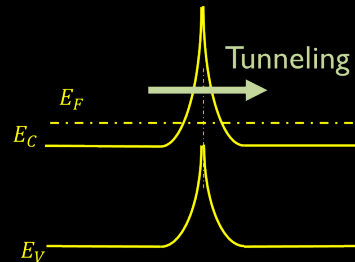
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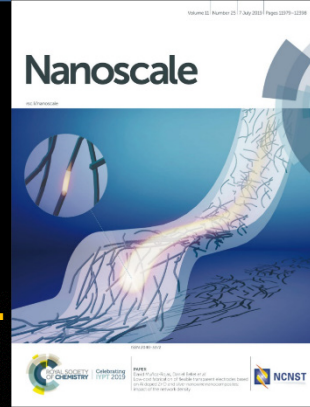
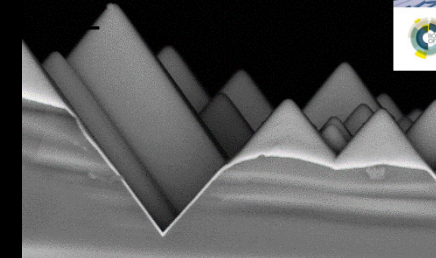
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We are recruiting PhDs and Postdocs



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Thanks for your attention!!!